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PART 2 RF EXPOSURE EVALUATION REPORT

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do, 16677, Korea Date of Testing: 07/21/2020 - 08/05/2020 Test Site/Location: PCTEST, Columbia, MD, USA Document Serial No.: 1M2004230075-25-R1.A3L

FCC ID:

A3LSMT978U

APPLICANT:

SAMSUNG ELECTRONICS CO., LTD.

DUT Type: Application Type: FCC Rule Part(s): Model: Device Serial Numbers: Portable Tablet Certification CFR §2.1093 SM-T978U Pre-Production Samples [SN: TF41746M, TFI17684M, 03735]

Note: This revised Test Report (S/N: 1M2004230075-25-R1.A3L) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them. Test results reported herein relate only to the item(s) tested.

Randy Ortanez President

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FCC ID: A3LSMT978U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 1 of 86
© 2020 PCTEST				REV 1.

REV 1.0 04/06/2020

TABLE OF CONTENTS

1	DEVICE	INDER TEST	3
2	RF EXPO	SURE LIMITS	5
3	TIME VAF	RYING TRANSMISSION TEST CASES	7
4	FCC MEA	SUREMENT PROCEDURES (FREQ < 6 GHZ)	10
5	FCC MEA	SUREMENT PROCEDURES (FREQ > 6 GHZ)	19
6	MEASUR	EMENT TEST SETUP (FREQ < 6 GHZ)	26
7	MEASUR	EMENT TEST SETUP (FREQ > 6 GHZ)	29
8	TEST CO	NFIGURATIONS (FREQ < 6 GHZ)	31
9	CONDUC	TED TX CASES (FREQ < 6 GHZ)	34
10	SYSTEM	VERIFICATION (FREQ < 6 GHZ)	54
11	SAR TES	T RESULTS (FREQ < 6 GHZ)	56
12	TEST CO	NFIGURATIONS (FREQ > 6 GHZ)	63
13	RADIATE	D POWER TX CASES (FREQ > 6 GHZ)	66
14	SYSTEM	VERIFICATION (FREQ > 6 GHZ)	77
15	POWER	DENSITY TEST RESULTS (FREQ > 6 GHZ)	78
16	EQUIPME	NT LIST	81
17	MEASUR	EMENT UNCERTAINTIES	82
18	CONCLU	SION	84
19	REFEREN	ICES	85
APPENI	DIX A:	VERIFICATION PLOTS	
APPENI	DIX B:	SAR TISSUE SPECIFICATIONS	
APPENI	DIX C:	SAR SYSTEM VALIDATION	
APPENI	DIX D:	TEST SETUP PHOTOGRAPHS	
APPENI	DIX E:	TEST SEQUENCES	
APPENI	DIX F:	TEST PROCEDURES FOR SUB6 NR + NR RADIO	

APPENDIX G: CALIBRATION CERTIFICATES

FCC ID: A3LSMT978U	PCTEST [®] Proud to be part of [®] element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:			
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 2 of 86	
© 2020 PCTEST				REV 1.0	

DEVICE UNDER TEST 1

1.1 **Device Overview**

Band & Mode	Operating Modes	Tx Frequency 826 40 - 846 60 MHz
UMTS 1750	Data	1712.4 - 1752.6 MHz
UMTS 1900	Data	1852.4 - 1907.6 MHz
LTE Band 71	Voice/Data	665.5 - 695.5 MHz
LTE Band 12	Voice/Data	699.7 - 715.3 MHz
LTE Band 13	Voice/Data	779.5 - 784.5 MHz
LTE Band 26 (Cell)	Voice/Data	814.7 - 848.3 MHz
LTE Band 5 (Cell)	Voice/Data	824.7 - 848.3 MHz
LTE Band 66 (AWS)	Voice/Data	1710.7 - 1779.3 MHz
LTE Band 4 (AWS)	Voice/Data	1710.7 - 1754.3 MHz
LTE Band 25 (PCS)	Voice/Data	1850.7 - 1914.3 MHz
LTE Band 2 (PCS)	Voice/Data	1850.7 - 1909.3 MHz
LTE Band 7	Voice/Data	2502.5 - 2567.5 MHz
LTE Band 41	Voice/Data	2498.5 - 2687.5 MHz
NR Band n71	Data	665.5 - 695.5 MHz
NR Band n5 (Cell)	Data	826.5 - 846.5 MHz
NR Band n66 (AWS)	Data	1712.5 - 1777.5 MHz
NR Band n25 (PCS)	Data	1852.5 - 1912.5 MHz
NR Band n2 (PCS)	Data	1852.5 - 1907.5 MHz
NR Band n41	Data	2506 - 2680 MHz
2.4 GHz WLAN	Data	2412 - 2462 MHz
U-NII-1	Data	5180 - 5240 MHz
U-NII-2A	Data	5260 - 5320 MHz
U-NII-2C	Data	5500 - 5720 MHz
U-NII-3	Data	5745 - 5825 MHz
Bluetooth	Data	2402 - 2480 MHz
NR Band n260	Data	37000 - 40000 MHz
NR Band n261	Data	27500 - 28350 MHz

1.2 Time-Averaging Algorithm for RF Exposure Compliance

The device under test (DUT) contains:

a. Qualcomm[®] SDX55M modem supporting 2G/3G/4G/5G NR WWAN Technologies

Qualcomm® SDX55M modem is enabled with Qualcomm® Smart Transmit feature. This feature performs time averaging algorithm in real time to control and manage transmitting power and ensure the time-averaged RF exposure is in compliance with FCC requirements all the time.

The Smart Transmit algorithm maintains the time-averaged transmit power, in turn, time-averaged RF exposure of SAR_design_target or PD_design_target, below the predefined time-averaged power limit (i.e., Plimit for sub-6 radio, and input power.limit for 5G mmW NR), for each characterized technology and band.

FCC ID: A3LSMT978U	PCTEST*	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 3 of 86
© 2020 PCTEST				REV 1.0

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Smart Transmit allows the device to transmit at higher power instantaneously, as high as P_{max} , when needed, but enforces power limiting to maintain time-averaged transmit power to P_{limit} for frequencies < 6 GHz and *input.power.limit* for frequencies > 6 GHz.

Note that the device uncertainty for sub-6GHz WWAN is 1.0dB for this DUT, the device uncertainty for mmW is 2.1 dB, and the reserve power margin is 3 dB.

This purpose of the Part 2 report is to demonstrate the DUT complies with FCC RF exposure requirement under Tx varying transmission scenarios, thereby validity of Qualcomm[®] Smart Transmit feature implementation in this device. It serves to compliment the Part 0 and Part 1 Test Reports to justify compliance per FCC.

1.3 Bibliography

Report Type	Report Serial Number
Part 0 SAR Test Report	1M2004230075 – 27-R1.A3L
Part 1 SAR Test Report	1M2004230075 – 01-R3.A3L
Part 0 Power Density Test Report	1M2004230075 – 23-R1.A3L
Part 1 Power Density Test Report	1M2004230075 – 24-R2.A3L
RF Exposure Compliance Summary	1M2004230075 – 26-R1.A3L

FCC ID: A3LSMT978U	Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Dava 4 st 00	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 4 of 86	
© 2020 PCTEST				REV 1	

REV 1.0 04/06/2020

2 **RF EXPOSURE LIMITS**

2.1 **Uncontrolled Environment**

UNCONTROLLED ENVIRONMENTS are defined as locations where there is the exposure of individuals who have no knowledge or control of their exposure. The general population/uncontrolled exposure limits are applicable to situations in which the general public may be exposed or in which persons who are exposed as a consequence of their employment may not be made fully aware of the potential for exposure or cannot exercise control over their exposure. Members of the general public would come under this category when exposure is not employment-related; for example, in the case of a wireless transmitter that exposes persons in its vicinity.

2.2 **Controlled Environment**

CONTROLLED ENVIRONMENTS are defined as locations where there is exposure that may be incurred by persons who are aware of the potential for exposure, (i.e. as a result of employment or occupation). In general, occupational/controlled exposure limits are applicable to situations in which persons are exposed as a consequence of their employment, who have been made fully aware of the potential for exposure and can exercise control over their exposure. This exposure category is also applicable when the exposure is of a transient nature due to incidental passage through a location where the exposure levels may be higher than the general population/uncontrolled limits, but the exposed person is fully aware of the potential for exposure and can exercise control over his or her exposure by leaving the area or by some other appropriate means.

2.3 **RF Exposure Limits for Frequencies Below 6 GHz**

HUMAN EXPOSURE LIMITS				
	UNCONTROLLED ENVIRONMENT General Population (W/kg) or (mW/g)	CONTROLLED ENVIRONMENT Occupational (W/kg) or (mW/g)		
Peak Spatial Average SAR _{Head}	1.6	8.0		
Whole Body SAR	0.08	0.4		
Peak Spatial Average SAR Hands, Feet, Ankle, Wrists, etc.	4.0	20		

Table 2-1 SAR Human Exposure Specified in ANSI/IEEE C95.1-1992 and Health Canada Safety Code 6

The Spatial Peak value of the SAR averaged over any 1 gram of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate 1. averaging time.

2. The Spatial Average value of the SAR averaged over the whole body.

The Spatial Peak value of the SAR averaged over any 10 grams of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate З averaging time.

FCC ID: A3LSMT978U	PCTEST [®] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 5 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
© 2020 PCTEST		·		REV 1.0	

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2.4 RF Exposure Limits for Frequencies Above 6 GHz

Per §1.1310 (d)(3), the MPE limits are applied for frequencies above 6 GHz. Power Density is expressed in units of W/m² or mW/cm².

Peak Spatially Averaged Power Density was evaluated over a circular area of 4 cm² per interim FCC Guidance for near-field power density evaluations per October 2018 TCB Workshop notes.

Table 2-2 Human Exposure Limits Specified in FCC 47 CFR §1.1310					
Human Exposure to Radiofrequency (RF) Radiation Limits					
Frequency Range [MHz]Power Density [mW/cm²]Averaging Time [Minutes]					
(A) Limit	s for Occupational / Controlled I	Environments			
1,500 - 100,000	5.0	6			
(B) Limits for General Population / Uncontrolled Environments					
1,500 – 100,000	1.0	30			

Note: 1.0 mW/cm² is 10 W/m²

2.5 Time Averaging Windows for FCC Compliance

Per October 2018 TCB Workshop Notes, the below time-averaging windows can be used for assessing timeaveraged exposures for devices that are capable of actively monitoring and adjusting power output over time to comply with exposure limits.

Interim Guidance	Frequency (GHz)	Maximum Averaging Time (sec)
SAR	< 3	100
SAN	3 – 6	60
	6 - 10	30
	10 - 16	14
	16 - 24	8
MPE	24 - 42	4
	42 - 95	2

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 6 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
© 2020 PCTEST		•		REV 1.0	

3 TIME VARYING TRANSMISSION TEST CASES

To validate the time averaging feature and demonstrate the compliance in Tx varying transmission conditions, the following transmission scenarios are covered in the Part 2 test:

- 1. During a time-varying Tx power transmission: To prove that the Smart Transmit feature accounts for Tx power variations in time accurately.
- 2. During a call disconnect and re-establish scenario: To prove that the Smart Transmit feature accounts for history of past Tx power transmissions accurately.
- 3. During a technology/band handover: To prove that the Smart Transmit feature functions correctly during transitions in technology/band.
- 4. During a DSI (Device State Index) change: To prove that the Smart Transmit feature functions correctly during transition from one device state (DSI) to another.
- 5. During an antenna (or beam) switch: To prove that the Smart Transmit feature functions correctly during transitions in antenna (such as AsDiv scenario) or beams (different antenna array configurations) or beams (different antenna array configurations).
- 6. SAR vs. PD exposure switching during sub-6+mmW transmission: To prove that the Smart Transmit feature functions correctly and ensures total RF exposure compliance during transitions in SAR dominant exposure, SAR+PD exposure, and PD dominant exposure scenarios.
- 7. During time window switch: To prove that the Smart Transmit feature correctly handles the transition from one time window to another specified by FCC, and maintains the normalized time-averaged RF exposure to be less than normalized FCC limit of 1.0 at all times.
- 8. SAR exposure switching between two active radios (radio1 and radio2): To prove that the Smart Transmit feature functions correctly and ensures total RF exposure compliance when exposure varies among SAR_radio1 only, SAR_radio1 + SAR_radio2, and SAR_radio2 only scenarios.

As described in Part 0 report, the RF exposure is proportional to the Tx power for a SAR- and PD-characterized wireless device. Thus, feature validation in Part 2 can be effectively performed through conducted (for f < 6GHz) and radiated (for $f \ge 6$ GHz) power measurement. Therefore, the compliance demonstration under dynamic transmission conditions and feature validation are done in conducted/radiated power measurement setup for transmission scenario 1 through 8.

To add confidence in the feature validation, the time-averaged SAR and PD measurements are also performed but only performed for transmission scenario 1 to avoid the complexity in SAR and PD measurement (such as, for scenario 3 requiring change in SAR probe calibration file to accommodate different bands and/or tissue simulating liquid).

The strategy for testing in Tx varying transmission condition is outlined as follows:

- Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's SAR and PD limits, through <u>time-averaged power</u> measurements
 - Measure conducted Tx power (for f < 6GHz) versus time, and radiated Tx power (EIRP for f > 10GHz) versus time.
 - Convert it into RF exposure and divide by respective FCC limits to get normalized exposure versus time.
 - o Perform running time-averaging over FCC defined time windows.
 - Demonstrate that the total normalized time-averaged RF exposure is less than 1 for all transmission scenarios (i.e., transmission scenarios 1, 2, 3, 4, 5, 6, 7, and 8) at all times.

FCC ID: A3LSMT978U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo Z of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 7 of 86

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REV 1.0 04/06/2020 Mathematical expression:

For < 6 GHz transmission only:

$$1g_{or_{1}0gSAR(t)} = \frac{conducted_{Tx_power(t)}}{conducted_{Tx_power_{limit}}} * 1g_{or_{1}0gSAR_{limit}}$$
(1a)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_or_10gSAR(t)dt}{FCC SAR limit} \le 1$$
(1b)

For sub-6+mmW transmission:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(2a)

$$4cm^{2}PD(t) = \frac{radiated_{Tx_power(t)}}{radiated_{Tx_power_input.power.limit}} * 4cm^{2}PD_input.power.limit$$

04/06/2020

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{or_{-}10gSAR(t)dt}}{FCC\,SAR\,limit} + \frac{\frac{1}{T_{PD}}\int_{t-T_{PD}}^{t} 4cm^{2}PD(t)dt}{FCC\,4cm^{2}\,PD\,limit} \le 1$$
(2c)

- where, *conducted_Tx_power(t)*, *conducted_Tx_power_P_{limit}*, and 1g_or_10gSAR_P_{limit} correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *P_{limit}*, and measured 1gSAR *or 10gSAR* values at *P_{limit}* corresponding to sub-6 transmission. Similarly, *radiated_Tx_power(t)*, *radiated_Tx_power_input.power.limit*, and 4cm²PD_input.power.limit correspond to the measured instantaneous radiated Tx power, radiated Tx power at *input.power.limit* (i.e., radiated power limit), and 4cm²PD value at *input.power.limit* corresponding to mmW transmission. Both *P_{limit}* and *input.power.limit* are the parameters pre-defined in Part 0 and loaded via Embedded File System (EFS) onto the EUT. *T*_{SAR} is the FCC defined time window for sub-6 radio; *T_{PD}* is the FCC defined time window for mmW radio.
 - Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's SAR and PD limits, through time-averaged SAR and PD measurements. Note as mentioned earlier, this measurement is performed for transmission scenario 1 only.
 - For sub-6 transmission only, measure instantaneous SAR versus time; for LTE+sub6 NR transmission, request low power (or all-down bits) on LTE so that measured SAR predominantly corresponds to sub6 NR.
 - For LTE + mmW transmission, measure instantaneous E-field versus time for mmW radio and instantaneous conducted power versus time for LTE radio.
 - Convert it into RF exposure and divide by respective FCC limits to obtain normalized exposure versus time.
 - Perform time averaging over FCC defined time window.
 - Demonstrate that the total normalized time-averaged RF exposure is less than 1 for transmission scenario 1 at all times.

FCC ID: A3LSMT978U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 8 of 86
© 2020 PCTEST				REV 1.0

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Mathematical expression:

For sub-6 transmission only:

$$1g_or_10gSAR(t) = \frac{pointSAR(t)}{pointSAR_P_{limit}} * 1g_or_10gSAR(t)_P_{limit}$$
(3a)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC SAR limit} \le 1$$
(3b)

For LTE+mmW transmission:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(4a)

 $4cm^2 PD(t) = \frac{[pointE(t)]^2}{[pointE_input.power.limit]^2} * 4cm^2 PD_input.power.limit$ (4b)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_or_10gSAR(t)dt}{FCC SAR limit} + \frac{\frac{1}{T_{PD}}\int_{t-T_{PD}}^{t} 4cm^{2}PD(t)dt}{FCC 4cm^{2}PD limit} \le 1$$
(4c)

where, pointSAR(t), $pointSAR_{limit}$, and $1g_{or}_{10}gSAR_{limit}$ correspond to the measured instantaneous point SAR, measured point SAR at P_{limit} , and measured 1gSAR or 10gSAR values at P_{limit} corresponding to sub-6 transmission. Similarly, pointE(t), $pointE_{input.power.limit}$, and $4cm^2PD_{input.power.limit}$ correspond to the measured instantaneous E-field, E-field at *input.power.limit*, and $4cm^2PD$ value at *input.power.limit* corresponding to mmW transmission.

Note: cDASY6 measurement system by Schmid & Partner Engineering AG (SPEAG) of Zurich, Switzerland measures relative E-field, and provides ratio of $\frac{[pointE(t)]^2}{[pointE_input.power.limit]^2}$ versus time.

FCC ID: A3LSMT978U	PCTEST [*] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 9 of 86
© 2020 PCTEST				REV 1.0

04/06/2020

4 FCC MEASUREMENT PROCEDURES (FREQ < 6 GHZ)

This chapter provides the test plan and test procedure for validating Qualcomm Smart Transmit feature for sub-6 transmission. The 100 seconds time window for operating f < 3GHz is used as an example to detail the test procedures in this chapter. The same test plan and test procedures described in this chapter apply to 60 seconds time window for operating $f \ge 3GHz$.

4.1 Test sequence determination for validation

Following the FCC recommendation, two test sequences having time-variation in Tx power are predefined for sub-6 (f < 6 GHz) validation:

- Test sequence 1: request DUT's Tx power to be at maximum power, measured P_{max}^{\dagger} , for 80s, then . requesting for half of the maximum power, i.e., measured $P_{max}/2$, for the rest of the time.
- Test sequence 2: request DUT's Tx power to vary with time. This sequence is generated relative to • measured P_{max}, measured P_{limit} and calculated P_{reserve} (= measured P_{limit} in dBm - Reserve power margin in dB) of DUT based on measured Plimit.

The details for generating these two test sequences is described and listed in Appendix E.

For test sequence generation, "measured P_{limit} " and "measured P_{max} " are used instead of the " P_{limit} " NOTE specified in EFS entry and " P_{max} " specified for the device, because the Smart Transmit feature operates against the actual power level of the "Plimit" that was calibrated for the DUT. The "measured *P_{limit}*" accurately reflects what the feature is referencing to, therefore, it should be used during feature validation testing. The RF tune up and device-to-device variation are already considered in Part 0 report prior to determining Plimit.

4.2 Test configuration selection criteria for validating Smart Transmit feature

For validating the Smart Transmit feature, this section provides the general guidance to select test cases.

4.2.1 Test configuration selection for time-varying Tx power transmission

The Smart Transmit time averaging feature operation is independent of bands, modes, and channels for a given technology. Hence, validation of Smart Transmit in one band/mode/channel per technology is sufficient. Two bands per technology are proposed and selected for this testing to provide high confidence in this validation.

The criteria for the selection are based on the Piimit values determined in Part 0 report. Select two bands* in each supported technology that correspond to least** and highest*** Plimit values that are less than Pmax for validating Smart Transmit.

* If one *P*_{limit} level applies to all the bands within a technology, then only one band needs to be tested. In this case, within the bands having the same Plimit, the radio configuration (e.g., # of RBs, channel#) and device position that correspond to the highest measured 1gSAR at Plimit shown in Part 1 report is selected.

** In case of multiple bands having the same least *Plimit* within the technology, then select the band having the highest measured 1gSAR at Plimit.

*** The band having a higher Plimit needs to be properly selected so that the power limiting enforced by Smart Transmit can be validated using the pre-defined test sequences. If the highest Plimit in a technology is too high where the power limiting enforcement is not needed when testing with the pre-defined test sequences, then the

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dama 40 of 00
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 10 of 86
(2020 PCTEST				REV 1.0

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next highest level is checked. This process is continued within the technology until the second band for validation testing is determined.

4.2.2 Test configuration selection for change in call

The criteria to select a test configuration for call-drop measurement is:

- Select technology/band with least Plimit among all supported technologies/bands, and select the radio configuration (e.g., # of RBs, channel#) in this technology/band that corresponds to the highest measured 1gSAR at Plimit listed in Part 1 report.
- In case of multiple bands having same least *P*limit, then select the band having the highest measured 1gSAR at *P*_{limit} in Part 1 report.

This test is performed with the DUT's Tx power requested to be at maximum power, the above band selection will result in Tx power enforcement (i.e., DUT forced to have Tx power at Preserve) for longest duration in one FCC defined time window. The call change (call drop/reestablish) is performed during the Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at Preserve). One test is sufficient as the feature operation is independent of technology and band.

4.2.3 Test configuration selection for change in technology/band

The selection criteria for this measurement is, for a given antenna, to have DUT switch from a technology/band with lowest Plimit within the technology group (in case of multiple bands having the same Plimit, then select the band with highest measured 1gSAR at Plimit) to a technology/band with highest Plimit within the technology group, in case of multiple bands having the same Plimit, then select the band with lowest measured 1gSAR at Plimit in Part 1 report, or vice versa.

This test is performed with the DUT's Tx power requested to be at maximum power, the technology/band switch is performed during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at Preserve).

4.2.4 Test configuration selection for change in DSI

The criteria to select a test configuration for DSI change test is

Select a technology/band having the $P_{limit} < P_{max}$ within any technology and DSI group, and for the same technology/band having a different Plimit in any other DSI group. Note that the selected DSI transition need to be supported by the device.

This test is performed with the DUT's Tx power requested to be at maximum power in selected technology/band. and DSI change is conducted during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at Preserve).

Test configuration selection for SAR exposure switching 4.2.5

If supported, the test configuration for SAR exposure switching should cover

- 1. SAR exposure switch when two active radios are in the same time window
- 2. SAR exposure switch when two active radios are in different time windows. One test with two active radios in any two different time windows is sufficient as Smart Transmit operation is the same for RF exposure switch in any combination of two different time windows. For device supporting LTE + mmW NR, this test is covered in SAR vs PD exposure switch validation.

The Smart Transmit time averaging operation is independent of the source of SAR exposure (for example, LTE vs. Sub6 NR) and ensures total time-averaged RF exposure compliance. Hence, validation of Smart Transmit in any one simultaneous SAR transmission scenario (i.e., one combination for LTE + Sub6 NR transmission) is sufficient, where the SAR exposure varies among SAR_{radio1} only, SAR_{radio1} + SAR_{radio2}, and SAR_{radio2} only scenarios.

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dama 44 of 00
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 11 of 86
C	2020 PCTEST				REV 1.0

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The criteria to select a test configuration for validating Smart Transmit feature during SAR exposure switching scenarios is

- Select any two < 6GHz technologies/bands that the EUT supports simultaneous transmission (for example, LTE+Sub6 NR).
- Among all supported simultaneous transmission configurations, the selection order is
 - 1. select one configuration where both P_{limit} of radio1 and radio2 is less than their corresponding P_{max} , preferably, with different P_{limits} . If this configuration is not available, then,
 - 2. select one configuration that has P_{limit} less than its P_{max} for at least one radio. If this can not be found, then,
 - 3. select one configuration that has P_{limit} of radio1 and radio2 greater than P_{max} but with least ($P_{limit} P_{max}$) delta.

Test for one simultaneous transmission scenario is sufficient as the feature operation is the same.

4.3 Test procedures for conducted power measurements

This section provides general conducted power measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 3. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

4.3.1 Time-varying Tx power transmission scenario

This test is performed with the two pre-defined test sequences described in Section 4.1 for all the technologies and bands selected in Section 4.2.1. The purpose of the test is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged SAR (corresponding time-averaged Tx power) does not exceed the FCC limit at all times (see Eq. (1a) and (1b)).

Test procedure

- Measure *P_{max}*, measure *P_{limit}* and calculate *P_{reserve}* (= measured *P_{limit}* in dBm *Reserve_power_margin* in dB) and follow Section 4.1 to generate the test sequences for all the technologies and bands selected in Section 4.2.1. Both test sequence 1 and test sequence 2 are created based on measured *P_{max}* and measured *P_{limit}* of the DUT. Test condition to measure *P_{max}* and *P_{limit}* is:
 - a. Measure *P_{max}* with Smart Transmit <u>disabled</u> and callbox set to request maximum power.
 - b. Measure *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve_power_margin to actual (intended) value (3dB for this DUT based on Part 1 report) and reset power on DUT to enable Smart Transmit, establish radio link in desired radio configuration, with callbox requesting the DUT's Tx power to be at pre-defined test sequence 1, measure and record Tx power versus time, and then convert the conducted Tx power into 1gSAR or 10gSAR value (see Eq. (1a)) using measured *P*_{limit} from above Step 1. Perform running time average to determine time-averaged power and 1gSAR or 10gSAR versus time as illustrated in Figure 4-1 where using 100-seconds time window as an example.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 40 at 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 12 of 86
© 2020 PCTEST		•		REV 1.0

REV 1.0 04/06/2020

Note: In Eq.(1a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band/antenna/DSI reported in Part 1 report.

Note: For an easier computation of the running time average, 0 dBm can be added at the beginning of the test sequences the length of the responding time window, for example, add 0dBm for 100-seconds so the running time average can be directly performed starting with the first 100-seconds data using excel spreadsheet. This technique applies to all tests performed in this Part 2 report for easier time-averaged computation using excel spreadsheet.

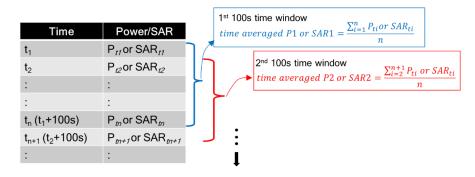


Figure 4-1 Running Average Illustration

- 3. Make one plot containing:
 - a. Instantaneous Tx power versus time measured in Step 2,
 - b. Requested Tx power used in Step 2 (test sequence 1),
 - c. Computed time-averaged power versus time determined in Step 2,
 - d. Time-averaged power limit (corresponding to FCC SAR limit of 1.6 W/kg for 1gSAR or 4.0W/kg for 10gSAR) given by

 $Time \ avearged \ power \ limit = meas. P_{limit} + 10 \times \log(\frac{FCC \ SAR \ limit}{meas.SAR_Plimit})$ (5a)

where *meas*. P_{limit} and *meas*. *SAR_Plimit* correspond to measured power at P_{limit} and measured SAR at P_{limit} .

- 4. Make another plot containing:
 - a. Computed time-averaged 1gSAR or 10gSAR versus time determined in Step 2
 - b. FCC 1gSARlimit of 1.6W/kg or FCC 10gSARlimit of 4.0W/kg.
- 5. Repeat Steps 2 ~ 4 for pre-defined test sequence 2 and replace the requested Tx power (test sequence 1) in Step 2 with test sequence 2.
- 6. Repeat Steps 2 ~ 5 for all the selected technologies and bands.
- 7. The validation criteria are, at all times, the time-averaged power versus time shown in Step 3 plot shall not exceed the time-averaged power limit (defined in Eq. (5a)), in turn, the time-averaged 1gSAR or 10gSAR versus time shown in Step 4 plot shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (1b)).

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 40 - 6 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 13 of 86
0 2020 PCTEST				REV 1 (

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4.3.2 Change in call scenario

This test is to demonstrate that Smart Transmit feature accurately accounts for the past Tx powers during time-averaging when a new call is established.

The call disconnect and re-establishment needs to be performed during power limit enforcement, i.e., when the DUT's Tx power is at Preserve level, to demonstrate the continuity of RF exposure management and limiting in call change scenario. In other words, the RF exposure averaged over any FCC defined time window (including the time windows containing the call change) doesn't exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

Test procedure

- 1. Measure Plimit for the technology/band selected in Section 4.2.2. Measure Plimit with Smart Transmit enabled and Reserve_power_margin set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve_power_margin to actual (intended) value and reset power on DUT to enable Smart Transmit.
- Establish radio link with callbox in the selected technology/band.
- 4. Request DUT's Tx power at 0 dBm for at least one time window specified for the selected technology/band, followed by requesting DUT's Tx power to be at maximum power for about ~60 seconds, and then drop the call for ~10 seconds. Afterwards, re-establish another call in the same radio configuration (i.e., same technology/band/channel) and continue callbox requesting DUT's Tx power to be at maximum power for the remaining time of at least another full duration of the specified time window. Measure and record Tx power versus time. Once the measurement is done, extract instantaneous Tx power versus time, convert the measured conducted Tx power into 1gSAR or 10gSAR value using Eq. (1a), and then perform the running time average to determine time-averaged power and 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(1a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 5. Make one plot containing: (a) instantaneous Tx power versus time, (b) requested power, (c) computed time-averaged power, (d) time-averaged power limit calculated using Eq.(5a).
- 6. Make another plot containing: (a) computed time-averaged 1gSAR or 10gSAR versus time, and (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

The validation criteria are, at all times, the time-averaged power versus time shall not exceed the timeaveraged power limit (defined in Eq.(5a)), in turn, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (1b)).

4.3.3 Change in technology and band

This test is to demonstrate the correct power control by Smart Transmit during technology switches and/or band handovers.

Similar to the change in call test in Section 4.3.2, to validate the continuity of RF exposure limiting during the transition, the technology and band handover needs to be performed when DUT's Tx power is at Preserve level (i.e., during Tx power enforcement) to make sure that the DUT's Tx power from previous Preserve level to the new Preserve level (corresponding to new technology/band). Since the Plimit could vary with technology and band, Eq. (1a) can be written as follows to convert the instantaneous Tx power in 1gSAR or 10gSAR exposure for the two given radios, respectively:

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
	Document S/N:	Test Dates:	DUT Type:			
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 14 of 86	
© 2020 PCTEST					REV 1.0)

2020 PCTEST

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$$1g_or_10gSAR_1(t) = \frac{conducted_Tx_power_1(t)}{conducted_Tx_power_P_{limit_1}} * 1g_or_10gSAR_P_{limit_1}$$
(6a)

$$1g_{or_{1}0gSAR_{2}(t)} = \frac{conducted_{Tx_power_{2}(t)}}{conducted_{Tx_power_{P_{limit_{2}}}}} * 1g_{or_{1}0gSAR_{P_{limit_{2}}}}$$
(6b)

$$\frac{1}{T_{SAR}} \left[\int_{t-T_{SAR}}^{t_1} \frac{1g_or_10gSAR_1(t)}{FCC\,SAR\,limit} dt + \int_{t-T_{SAR}}^{t} \frac{1g_or_10gSAR_2(t)}{FCC\,SAR\,limit} dt \right] \le 1$$
(6c)

where, *conducted_Tx_power_1(t)*, *conducted_Tx_power_Plimit_1*, and *1g_or_10gSAR_Plimit_1* correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *Plimit_1* and measured *1gSAR* or *10gSAR* value at *Plimit* of technology1/band1; *conducted_Tx_power_2(t)*, *conducted_Tx_power_Plimit_2(t)*, and *1g_or_10gSAR_Plimit_2* correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *Plimit_1*, and measured *1gSAR* or *10gSAR* value at *Plimit_1* of technology2/band2. Transition from technology1/band1 to the technology2/band2 happens at time-instant 't₁'.

Test procedure

- 1. Measure *P*_{limit} for both the technologies and bands selected in Section 4.2.3. Measure *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
- Set Reserve_power_margin to actual (intended) value and reset power on DUT to enable Smart Transmit
- 3. Establish radio link with callbox in first technology/band selected.
- 4. Request DUT's Tx power at 0 dBm for at least one time window specified for the selected technology/band, followed by requesting DUT's Tx power to be at maximum power for about ~60 seconds, and then switch to second technology/band selected. Continue with callbox requesting DUT's Tx power to be at maximum power for the remaining time of at least another full duration of the specified time window. Measure and record Tx power versus time for the full duration of the test.
- 5. Once the measurement is done, extract instantaneous Tx power versus time, and convert the conducted Tx power into 1gSAR or 10gSAR value using Eq. (6a) and (6b) and corresponding measured *P*_{limit} values from Step 1 of this section. Perform the running time average to determine time-averaged power and 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(6a) & (6b), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 6. Make one plot containing: (a) instantaneous Tx power versus time, (b) requested power, (c) computed time-averaged power, (d) time-averaged power limit calculated using Eq.(5a).
- Make another plot containing: (a) computed time-averaged 1gSAR or 10gSAR versus time, and (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

The validation criteria are, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (6c)).

4.3.4 Change in DSI

This test is to demonstrate the correct power control by Smart Transmit during DSI switches from one DSI to another. The test procedure is identical to Section 4.3.3, by replacing technology/band switch operation with DSI switch. The validation criteria are, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 15 of 86
© 2020 PCTEST	· · · · · · · · · · · · · · · · · · ·			REV 1.0

4.3.5 SAR exposure switching

This test is to demonstrate that Smart Transmit feature is accurately accounts for switching in exposures among SAR from radio1 only, SAR from both radio1 and radio2, and SAR from radio2 only scenarios, and ensures total time-averaged RF exposure complies with the FCC limit. Here, radio1 represents primary radio (for example, LTE anchor in a NR non-standalone mode call) and radio2 represents secondary radio (for example, sub6 NR or mmW NR). The detailed test procedure for SAR exposure switching in the case of LTE+Sub6 NR non-standalone mode transmission scenario is provided in APPENDIX F:..

Test procedure:

- 1. Measure conducted Tx power corresponding to Plimit for radio1 and radio2 in selected band. Test condition to measure conducted *P*_{limit} is:
 - Establish device in call with the callbox for radio1 technology/band. Measure conducted Tx power corresponding to radio1 Plimit with Smart Transmit enabled and Reserve power margin set to 0 dB, callbox set to request maximum power.
 - □ Repeat above step to measure conducted Tx power corresponding to radio2 <u>*Plimit*</u>. If radio2 is dependent on radio1 (for example, non-standalone mode of Sub6 NR requiring radio1 LTE as anchor), then establish radio1 + radio2 call with callbox, and request all down bits for radio1 LTE. In this scenario, with callbox requesting maximum power from radio2 Sub6 NR, measured conducted Tx power corresponds to radio2 Plimit (as radio1 LTE is at all-down bits)
- 2. Set Reserve_power_margin to actual (intended) value, with EUT setup for radio1 + radio2 call. In this description, it is assumed that radio2 has lower priority than radio1. Establish device in radio1+radio2 call, and request all-down bits or low power on radio1, with callbox requesting EUT's Tx power to be at maximum power in radio2 for at least one time window. After one time window, set callbox to request EUT's Tx power to be at maximum power on radio1, i.e., all-up bits. Continue radio1+radio2 call with both radios at maximum power for at least one time window, and drop (or request all-down bits on) radio2. Continue radio1 at maximum power for at least one time window. Record the conducted Tx power for both radio1 and radio2 for the entire duration of this test.
- Once the measurement is done, extract instantaneous Tx power versus time for both radio1 and radio2 links. Convert the conducted Tx power for both these radios into 1gSAR or 10gSAR value (see Eq. (6a) and (6b)) using corresponding technology/band Plimit measured in Step 1, and then perform the running time average to determine time-averaged 1gSAR or 10gSAR versus time.
- 4. Make one plot containing: (a) instantaneous Tx power versus time measured in Step 2.
- 5. Make another plot containing: (a) instantaneous 1gSAR versus time determined in Step 3, (b) computed time-averaged 1gSAR versus time determined in Step 3, and (c) corresponding regulatory 1gSAR_{limit} of 1.6W/kg or 10gSAR_{limit} of 4.0W/kg.

The validation criteria is, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the regulatory 1gSARlimit of 1.6W/kg or 10gSARlimit of 4.0W/kg.

FCC ID: A3LSMT978U	PCTEST* Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 46 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 16 of 86
© 2020 PCTEST				

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4.4 Test procedure for time-varying SAR measurements

This section provides general time-varying SAR measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 3. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

To perform the validation through SAR measurement for transmission scenario 1 described in Section 3, the "path loss" between callbox antenna and DUT needs to be calibrated to ensure that the DUT Tx power reacts to the requested power from callbox in a radiated call. It should be noted that when signaling in closed loop mode, protocol-level power control is in play, resulting in DUT not solely following callbox TPC (Tx power control) commands. In other words, DUT response has many dependencies (RSSI, quality of signal, path loss variation, fading, etc.,) other than just TPC commands. These dependencies have less impact in conducted setup (as it is a controlled environment and the path loss can be very well calibrated) but have significant impact on radiated testing in an uncontrolled environment, such as SAR test setup. Therefore, the deviation in DUT Tx power from callbox requested power is expected, however the time-averaged SAR should not exceed FCC SAR requirement at all times as Smart Transmit controls Tx power at DUT.

The following steps are for time averaging feature validation through SAR measurement:

- 1. "Path Loss" calibration: Place the DUT against the phantom in the worst-case position determined based on Section 4.2.1. For each band selected, prior to SAR measurement, perform "path loss" calibration between callbox antenna and DUT. Since the SAR test environment is not controlled and well calibrated for OTA (Over the Air) test, extreme care needs to be taken to avoid the influence from reflections. The test setup is described in Section 6.2.
- 2. Time averaging feature validation:
 - For a given radio configuration (technology/band) selected in Section 4.2.1, enable Smart i Transmit and set Reserve_power_margin to 0 dB, with callbox to request maximum power, perform area scan, conduct pointSAR measurement at peak location of the area scan. This point SAR value, pointSAR Plimit, corresponds to point SAR at the measured Plimit (i.e., measured Plimit from the DUT in Step 1 of Section 4.3.1).
 - ii Set Reserve power margin to actual (intended) value and reset power on DUT to enable Smart Transmit. Note, if Reserve_power_margin cannot be set wirelessly, care must be taken to reposition the DUT in the exact same position relative to the SAM phantom as in above Step 2.i. Establish radio link in desired radio configuration, with callbox requesting the DUT's Tx power at power levels described by test sequence 1 generated in Step 1 of Section 4.3.1, conduct point SAR measurement versus time at peak location of the area scan determined in Step 2.i of this section. Once the measurement is done, extract instantaneous point SAR vs time data, pointSAR(t), and convert it into instantaneous 1gSAR or 10gSAR vs. time using Eq. (3a), rewritten below:

$$1g_or_10gSAR(t) = \frac{pointSAR(t)}{pointSAR_P_{limit}} * 1g_or_10gSAR_P_{limit}$$

where, $pointSAR_{Plimit}$ is the value determined in Step 2.i, and pointSAR(t) is the instantaneous point SAR measured in Step 2.ii, 1g_or_10gSAR_P_{limit} is the measured 1gSAR or 10gSAR value listed in Part 1 report.

04/06/2020

- iii Perform 100s running average to determine time-averaged 1gSAR or 10gSAR versus time.
- Make one plot containing: (a) time-averaged 1gSAR or 10gSAR versus time determined in Step iv 2.iii of this section, (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.
- Repeat 2.ii ~ 2.iv for test sequence 2 generated in Step 1 of Section 4.3.1. v
- vi Repeat 2.i ~ 2.v for all the technologies and bands selected in Section 4.2.1.

FCC ID: A3LSMT978U	PCTEST [*] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 17 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 17 of 86
© 2020 PCTEST				REV 1 (

© 2020 PCTEST

The time-averaging validation criteria for SAR measurement is that, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (3b)).

FCC ID: A3LSMT978U	Proved to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 18 of 86
© 2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

5 FCC MEASUREMENT PROCEDURES (FREQ > 6 GHZ)

This section provides the test plan and test procedures for validating Qualcomm Smart Transmit feature for mmW transmission. For this EUT, millimeter wave (mmW) transmission is only in non-standalone mode, i.e., it requires an LTE link as anchor.

5.1 Test sequence for validation in mmW NR transmission

In 5G mmW NR transmission, the test sequence for validation is with the callbox requesting EUT's Tx power in 5G mmW NR at maximum power all the time.

5.2 Test configuration selection criteria for validating Smart Transmit feature

Test configuration selection for time-varying Tx power transmission 5.2.1

The Smart Transmit time averaging feature operation is independent of bands, modes, channels, and antenna configurations (beams) for a given technology. Hence, validation of Smart Transmit in any one band/mode/channel per technology is sufficient.

5.2.2 Test configuration selection for change in antenna configuration (beam)

The Smart Transmit time averaging feature operation is independent of bands, modes, channels, and antenna configurations (beams) for a given technology. Hence, validation of Smart Transmit with beam switch between any two beams is sufficient.

5.2.3 Test configuration selection for SAR vs. PD exposure switch during transmission

The Smart Transmit time averaging feature operation is independent of the nature of exposure (SAR vs. PD) and ensures total time-averaged RF exposure compliance. Hence, validation of Smart Transmit in any one band/mode/channel/beam for mmW + sub-6 (LTE) transmission is sufficient, where the exposure varies among SAR dominant scenario, SAR+PD scenario, and PD dominant scenario.

5.3 Test procedures for mmW radiated power measurements

Perform conducted power measurement (for f < 6GHz) and radiated power measurement (for f > 6GHz) for LTE + mmW transmission to validate Smart Transmit time averaging feature in the various transmission scenarios described in Section 3.

This section provides general conducted power measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 3. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

5.3.1 Time-varying Tx power scenario

The purpose of the test is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged Tx power when converted into RF exposure values does not exceed the FCC limit at all times (see Eq. (2a), (2b) & (2c) in Section 3).

Test procedure:

Measure conducted Tx power corresponding to Plimit for LTE in selected band, and measure radiated Tx power corresponding to input.power.limit in desired mmW band/channel/beam by following below steps:

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 10 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 19 of 86
2020 PCTEST				REV 1 (

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- Measure radiated power corresponding to mmW input.power.limit by setting up the EUT's Tx a. power in desired band/channel/beam at input.power.limit in Factory Test Mode (FTM). This test is performed in a calibrated anechoic chamber. Rotate the EUT to obtain maximum radiated Tx power, keep the EUT in this position and do not disturb the position of the EUT inside the anechoic chamber for the rest of this test.
- Reset EUT to place in online mode and establish radio link in LTE, measure conducted Tx b. power corresponding to LTE Plimit with Smart Transmit enabled and Reserve_power_margin set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve power margin to actual (intended) value and reset power on EUT to enable Smart Transmit. With EUT setup for a mmW NR call in the desired/selected LTE band and mmW NR band, perform the following steps:
 - Establish LTE and mmW NR connection in desired band/channel/beam used in Step 1. As soon as the mmW connection is established, immediately request all-down bits on LTE link. With callbox requesting EUT's Tx power to be at maximum mmW power to test predominantly PD exposure scenario (as SAR exposure is less when LTE's Tx power is at low power).
 - b. After 120s, request LTE to go all-up bits for at least 100s. SAR exposure is dominant. There are two scenarios:
 - If *P*_{limit} < *P*_{max} for LTE, then the RF exposure margin (provided to mmW NR) gradually runs i out (due to high SAR exposure). This results in gradual reduction in the 5G mmW NR transmission power and eventually seized 5G mmW NR transmission when LTE goes to Preserve level.
 - If $P_{limit} \ge P_{max}$ for LTE, then the 5G mmW NR transmission's averaged power should ii gradually reduce but the mmW NR connection can sustain all the time (assuming TxAGC uncertainty = 0dB).
 - Record the conducted Tx power of LTE and radiated Tx power of mmW for the full duration of c. this test of at least 300s.
- Once the measurement is done, extract instantaneous Tx power versus time for both LTE and mmW links. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using Eq. (2a) and Plimit measured in Step 1.b, and then divide by FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR to obtain instantaneous normalized 1gSAR or 10gSAR versus time. Perform 100s running average to determine normalized 100s-averaged 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(2a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at Plimit for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 4. Similarly, convert the radiated Tx power for mmW into 4cm²PD value using Eq. (2b) and the radiated Tx power limit (i.e., radiated Tx power at *input.power.limit*) measured in Step 1.a, then divide by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
 - NOTE: In Eq.(2b), instantaneous radiated Tx power is converted into instantaneous 4cm²PD by applying the worst-case 4cm²PD value measured at input power limit for the selected band/beam in Part 1 report.
- 5. Make one plot containing: (a) instantaneous conducted Tx power for LTE versus time, (b) computed 100s-averaged conducted Tx power for LTE versus time, (c) instantaneous radiated Tx power for

04/06/2020

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 86
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 20 of 86
2020 PCTEST				REV 1 (

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mmW versus time, as measured in Step 2, (d) computed 4s-averaged radiated Tx power for mmW versus time, and (e) time-averaged conducted and radiated power limits for LTE and mmW radio using Eq. (5a) & (5b), respectively:

Time avearged LTE power limit = meas. $P_{limit} + 10 \times \log(\frac{FCC SAR limit}{meas.SAR_Plimit})$ (5a)

FCC PD limit Time avearged mmW NR power limit = meas. $EIRP_{input.power.limit} + 10 \times \log(\frac{FCC PD limit}{meas.PD input.power.limit})$ (5b)

where meas. EIRP_{input,power.limit} and meas. PD_input. power. limit correspond to measured EIRP at input.power.limit and measured power density at input.power.limit.

6. Make another plot containing: (a) computed normalized 100s-averaged 1gSAR or 10gSAR versus time determined in Step 3, (b) computed normalized 4s-averaged 4cm²PD versus time determined in Step 4, and (c) corresponding total normalized time-averaged RF exposure (sum of steps (6.a) and (6.b)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 6.c shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., Eq. (2c)).

5.3.2 Switch in SAR vs. PD exposure during transmission

This test is to demonstrate that Smart Transmit feature is independent of the nature of exposure (SAR vs. PD), accurately accounts for switching in exposures among SAR dominant, SAR+PD, and PD dominant scenarios, and ensures total time-averaged RF exposure compliance.

Test procedure:

- 1. Measure conducted Tx power corresponding to Plimit for LTE in selected band, and measure radiated Tx power corresponding to input.power.limit in desired mmW band/channel/beam by following below steps:
 - Measure radiated power corresponding to *input.power.limit* by setting up the EUT's Tx power a. in desired band/channel/beam at input.power.limit in FTM. This test is performed in a calibrated anechoic chamber. Rotate the EUT to obtain maximum radiated Tx power, keep the EUT in this position and do not disturb the position of the EUT inside the anechoic chamber for the rest of this test.
 - Reset EUT to place in online mode and establish radio link in LTE, measure conducted Tx b. power corresponding to LTE Plimit with Smart Transmit enabled and Reserve_power_margin set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve power margin to actual (intended) value and reset power in EUT, with EUT setup for LTE + mmW call, perform the following steps:
 - Establish LTE (sub-6) and mmW NR connection with callbox. a.
 - As soon as the mmW connection is established, immediately request all-down bits on LTE b. link. Continue LTE (all-down bits) + mmW transmission for more than 100s duration to test predominantly PD exposure scenario (as SAR exposure is negligible from all-down bits in LTE).
 - After 120s, request LTE to go all-up bits, mmW transmission should gradually run out of RF c. exposure margin if LTE's Plimit < Pmax and seize mmW transmission (SAR only scenario); or mmW transmission should gradually reduce in Tx power and will sustain the connection if LTE's $P_{limit} > P_{max}$.
 - d. After 75s, request LTE to go all-down bits, mmW transmission should start getting back RF exposure margin and resume transmission again.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 21 of 90
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 21 of 86
2020 PCTEST				REV 1 (

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- e. Record the conducted Tx power of LTE and radiated Tx power of mmW for the entire duration of this test of at least 300s.
- 3. Once the measurement is done, extract instantaneous Tx power versus time for both LTE and mmW links. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using Eq. (2a) and Plimit measured in Step 1.b, and then divide by FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR to obtain instantaneous normalized 1gSAR or 10gSAR versus time. Perform 100s running average to determine normalized 100s-averaged 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(2a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 4. Similarly, convert the radiated Tx power for mmW into 4cm²PD value using Eq. (2b) and the radiated Tx power limit (i.e., radiated Tx power at *input.power.limit*) measured in Step 1.a, then divide this by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
 - NOTE: In Eq.(2b), instantaneous radiated Tx power is converted into instantaneous 4cm²PD by applying the worst-case 4cm²PD value measured at *input.power.limit* for the selected band/beam in Part 1 report.
- Make one plot containing: (a) instantaneous conducted Tx power for LTE versus time, (b) computed 100s-averaged conducted Tx power for LTE versus time, (c) instantaneous radiated Tx power for mmW versus time, as measured in Step 2, (d) computed 4s-averaged radiated Tx power for mmW versus time, and (e) time-averaged conducted and radiated power limits for LTE and mmW radio using Eq. (5a) & (5b), respectively.
- Make another plot containing: (a) computed normalized 100s-averaged 1gSAR or 10gSAR versus time determined in Step 3, (b) computed normalized 4s-averaged 4cm²PD versus time determined in Step 4, and (c) corresponding total normalized time-averaged RF exposure (sum of steps (6.a) and (6.b)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 6.c shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., Eq. (2c)).

5.3.3 Change in antenna configuration (beam)

This test is to demonstrate the correct power control by Smart Transmit during changes in antenna configuration (beam). Since the *input.power.limit* varies with beam, the Eq. (2a), (2b) and (2c) in Section 3 are written as below for transmission scenario having change in beam,

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(8a)

$$4cm^{2}PD_{1}(t) = \frac{radiated_{Tx}_power_1(t)}{radiated_{Tx}_power_input.power.limit_1} * 4cm^{2}PD_input.power.limit_1$$
(8b)

$$4cm^{2}PD_{2}(t) = \frac{radiated_{Tx}power_{2}(t)}{radiated_{Tx}power_{input}power_{init_{2}}} * 4cm^{2}PD_{input}power_{init_{2}}$$
(8c)

04/06/2020

FCC ID: A3LSMT978U	PCTEST [*] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 22 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 22 of 86
© 2020 PCTEST				REV 1.0

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$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC SAR limit} + \frac{\frac{1}{T_{PD}}\left[\int_{t-T_{PD}}^{t} 4cm^{2}\text{PD}_{1}(t)dt + \int_{t1}^{t} 4cm^{2}\text{PD}_{2}(t)dt\right]}{FCC4cm^{2}PD limit} \le 1$$
(8d)

where, *conducted_Tx_power(t)*, *conducted_Tx_power_P_{limit}*, and 1*g_or_10gSAR_P_{limit}* correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *P_{limit}*, and measured 1*gSAR or 10gSAR* values at *P_{limit}* corresponding to LTE transmission. Similarly, *radiated_Tx_power_1(t)*, *radiated_Tx_power_input.power.limit_1*, and 4*cm*²*PD_input.power.limit_1* correspond to the measured instantaneous radiated Tx power, radiated_Tx_power at *input.power.limit_1*, and 4*cm*²*PD_input.power.limit_1*, and 4*cm*²*PD_input.power.limit_2*, and 4*cm*²*PD_input.power.limit_2* correspond to the measured instantaneous radiated Tx power.limit_2 correspond to the measured instantaneous radiated Tx power, radiated Tx power.limit_2 correspond to the measured instantaneous radiated Tx power, radiated Tx power.limit.power.limit_2 correspond to the measured instantaneous radiated Tx power, radiated Tx power at *input.power.limit_2* correspond to the measured instantaneous radiated Tx power, radiated Tx power at *input.power.limit_2* corresponding to mmW transmission.

Test procedure:

- 1. Measure conducted Tx power corresponding to *P*_{limit} for LTE in selected band, and measure radiated Tx power corresponding to *input.power.limit* in desired mmW band/channel/beam by following below steps:
 - a. Measure radiated power corresponding to mmW *input.power.limit* by setting up the EUT's Tx power in desired band/channel at *input.power.limit* of beam 1 in FTM. Do not disturb the position of the EUT inside the anechoic chamber for the rest of this test. Repeat this Step 1.a for beam 2.
 - b. Reset EUT to place in online mode and establish radio link in LTE, measure conducted Tx power corresponding to LTE *P*_{limit} with Smart Transmit enabled and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
- 2. Set *Reserve_power_margin* to actual (intended) value and reset power in EUT, With EUT setup for LTE + mmW connection, perform the following steps:
 - a. Establish LTE (sub-6) and mmW NR connection in beam 1. As soon as the mmW connection is established, immediately request all-down bits on LTE link with the callbox requesting EUT's Tx power to be at maximum mmW power.
 - b. After beam 1 continues transmission for at least 20s, request the EUT to change from beam 1 to beam 2, and continue transmitting with beam 2 for at least 20s.
 - c. Record the conducted Tx power of LTE and radiated Tx power of mmW for the entire duration of this test.
- Once the measurement is done, extract instantaneous Tx power versus time for both LTE and mmW links. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using the similar approach described in Step 3 of Section 5.3.2. Perform 100s running average to determine normalized 100s-averaged 1gSAR versus time.
- 4. Similarly, convert the radiated Tx power for mmW NR into 4cm²PD value using Eq. (8b), (8c) and the radiated Tx power limits (i.e., radiated Tx power at *input.power.limit*) measured in Step 1.a for beam 1 and beam 2, respectively, and then divide the resulted PD values by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time for beam 1 and beam 2. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
 - NOTE: In Eq.(8b) and (8c), instantaneous radiated Tx power of beam 1 and beam 2 is converted into instantaneous 4cm²PD by applying the worst-case 4cm²PD value measured at the *input.power.limit* of beam 1 and beam 2 in Part 1 report, respectively.

04/06/2020

FCC ID: A3LSMT978U	PCTEST [*] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 22 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 23 of 86
© 2020 PCTEST				REV 1.0

2020 PGTEST

- 5. Since the measured radiated powers for beam 1 and beam 2 in Step 1.a were performed at an arbitrary rotation of EUT in anechoic chamber, repeat Step 1.a of this procedure by rotating the EUT to determine maximum radiated power at *input.power.limit* in FTM mode for both beams separately. Re-scale the measured instantaneous radiated power in Step 2.c by the delta in radiated power measured in Step 5 and the radiated power measured in Step 1.a for plotting purposes in next Step. In other words, this step essentially converts measured instantaneous radiated power for both beams. Perform 4s running average to compute 4s-avearged radiated Tx power. Additionally, use these EIRP values measured at *input.power.limit* at respective peak locations to determine the EIRP limits (using Eq. (5b)) for both these beams.
- 6. Make one plot containing: (a) instantaneous conducted Tx power for LTE versus time, (b) computed 100s-averaged conducted Tx power for LTE versus time, (c) instantaneous radiated Tx power for mmW versus time, as obtained in Step 5, (d) computed 4s-averaged radiated Tx power for mmW versus time, as obtained in Step 5, and (e) time-averaged conducted and radiated power limits for LTE and mmW radio, respectively.
- Make another plot containing: (a) computed normalized 100s-averaged 1gSAR versus time determined in Step 3, (b) computed normalized 4s-averaged 4cm²PD versus time determined in Step 4, and (c) corresponding total normalized time-averaged RF exposure (sum of steps (6.a) and (6.b)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 6.c shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., (8d)).

5.4 Test procedure for time-varying PD measurements

The following steps are used to perform the validation through PD measurement for transmission scenario 1 described in Section 3:

- 1. Place the EUT on the cDASY6 platform to perform PD measurement in the worst-case position/surface for the selected mmW band/beam. In PD measurement, the callbox is set to request maximum Tx power from EUT all the time. Hence, "path loss" calibration between callbox antenna and EUT is not needed in this test.
- 2. Time averaging feature validation:
 - a. Measure conducted Tx power corresponding to *P*_{*limit*} for LTE in selected band, and measure point E-field corresponding to *input.power.limit* in desired mmW band/channel/beam by following the below steps:
 - i. Measure conducted Tx power corresponding to LTE *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, with callbox set to request maximum power.
 - ii. Measure point E-field at peak location of fast area scan corresponding to input.power.limit by setting up the EUT's Tx power in desired mmW band/channel/beam at input.power.limit in FTM. Do not disturb the position of EUT and mmW cDASY6 probe.
 - b. Set *Reserve_power_margin* to actual value (i.e., intended value) and reset power on EUT, place EUT in online mode. With EUT setup for LTE (sub-6) + mmW NR call, as soon as the mmW NR connection is established, request all-down bits on LTE link. Continue LTE (all-down bits) + mmW transmission for more than 100s duration to test predominantly PD exposure scenario. After 120s, request LTE to go all-up bits, mmW transmission should gradually reduce. Simultaneously, record the conducted Tx power of LTE transmission using power meter and point E-field (in terms of ratio of <a href="mailto:lpointE(t)]² of mmW transmission using cDASY6 E-field probe at peak location identified in Step 2.a.ii for the entire duration of this test of at least 300s.

04/06/2020

FCC ID: A3LSMT978U	PCTEST [*] Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 24 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 24 of 86
© 2020 PCTEST				REV 1.0

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- c. Once the measurement is done, extract instantaneous conducted Tx power versus time for LTE transmission and [pointE(t)]²/[pointE_input.power.limit]² ratio versus time from cDASY6 system for mmW transmission. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using Eq. (4a) and Plimit measured in Step 2.a.i, and then divide this by FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR to obtain instantaneous normalized 1gSAR or 10gSAR versus time. Perform 100s running average to determine normalized 100s-averaged 1gSAR or 10gSAR versus time
 - NOTE: In Eq.(4a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band reported in Part 1 report.
- d. Similarly, convert the point E-field for mmW transmission into 4cm²PD value using Eq. (4b) and radiated power limit measured in Step 2.a.ii, and then divide this by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
- e. Make one plot containing: (i) computed normalized 100s-averaged 1gSAR or 10gSAR versus time determined in Step 2.c, (ii) computed normalized 4s-averaged 4cm²PD versus time determined in Step 2.d, and (iii) corresponding total normalized time-averaged RF exposure (sum of steps (2.e.i) and (2.e.ii)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 2.e.iii shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., Eq. (4c)).

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 25 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 25 of 86
© 2020 PCTEST	·			REV 1.0

2020 PCTEST

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6 MEASUREMENT TEST SETUP (FREQ < 6 GHZ)

6.1 Conducted Measurement Test setup

Legacy Test Setup

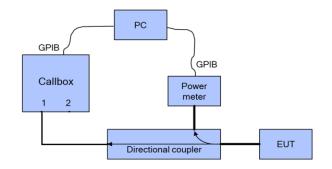
The Rohde & Schwarz CMW500 callbox was used in this test. The test setup schematic is shown in Figure 6-1a (Appendix D – Test Setup Photo 1) for measurements with a single antenna of DUT. For single antenna measurement, one port (RF1 COM) of the callbox is connected to the RF port of the DUT using a directional coupler. For technology/band switch measurement, one port (RF1 COM) of the callbox used for signaling two different technologies is connected to a combiner, which is in turn connected to a directional coupler. The other end of the directional coupler is connected to RF ports of the DUT corresponding to the antenna of interest. In the setups, power meter is used to tap the directional coupler for measuring the conducted output power of the DUT. For all legacy conducted tests, only RF1 COM port of the callbox is used to communicate with the DUT.

All the path losses from RF port of DUT to the callbox RF COM port and to the power meter are calibrated and automatically entered as offsets in the callbox and the power meter via test scripts on the PC used to control callbox and power meter.

LTE+Sub6 NR test setup:

LTE conducted port and Sub6 NR conducted port are same on this EUT (i.e., they share the same antenna), therefore, low-/high-pass filter are used to separate LTE and Sub6 NR signals for power meter measurement via directional couplers, as shown in below Figure 6-1b (Appendix D – Test Setup Photo 2).

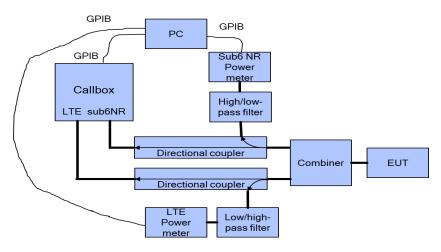
All the path losses from RF port of DUT to the callbox RF COM port and to the power meter are calibrated and automatically entered as offsets in the callbox and the power meter via test scripts on the PC used to control callbox and power meter.



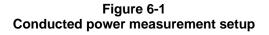
(a) Appendix D – Test Setup Photo 1

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 26 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 26 of 86

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(b) Appendix D – Test Setup Photo 2



Both the callbox and power meter are connected to the PC using GPIB cables. Two test scripts are custom made for automation, and the test duration set in the test scripts is 500 seconds.

For time-varying Tx power measurement, the PC runs the 1st test script to send GPIB commands to control the callbox's requested power versus time, while at the same time to record the conducted power measured at DUT RF port using the power meter. The commands sent to the callbox to request power are:

- 0dBm for 100 seconds
- test sequence 1 or test sequence 2 (defined in Section 4.1 and generated in Section 4.2.1), for 360 seconds
- stay at the last power level of test sequence 1 or test sequence 2 for the remaining time.

Power meter readings are periodically recorded every 100ms. A running average of this measured Tx power over 100 seconds is performed in the post-data processing to determine the 100s-time averaged power.

For call drop, technology/band/antenna switch, and DSI switch tests, after the call is established, the callbox is set to request the DUT's Tx power at 0dBm for 100 seconds while simultaneously starting the 2^{nd} test script runs at the same time to start recording the Tx power measured at DUT RF port using the power meter. After the initial 100 seconds since starting the Tx power recording, the callbox is set to request maximum power from the DUT for the rest of the test. Note that the call drop/re-establish, or technology/band/antenna switch or DSI switch is manually performed when the Tx power of DUT is at *P*_{reserve} level. See Section 4.3 for detailed test procedure of call drop test, technology/band/antenna switch test and DSI switch test.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 07 of 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 27 of 86
2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

6.2 SAR Measurement setup

The measurement setup is similar to normal SAR measurements as described in the Part 1 Test Report. The difference in SAR measurement setup for time averaging feature validation is that the callbox is signaling in close loop power control mode (instead of requesting maximum power in open loop control mode) and callbox is connected to the PC using GPIB so that the test script executed on PC can send GPIB commands to control the callbox's requested power over time (test sequence). The same test script used in conducted setup for time-varying Tx power measurements is also used in this section for running the test sequences during SAR measurements, and the recorded values from the disconnected power meter by the test script were discarded.

As mentioned in Section 4.4, for DUT to follow TPC command sent from the callbox wirelessly, the "path loss" between callbox antenna and the DUT needs to be very well calibrated. Since the SAR chamber is in uncontrolled environment, precautions must be taken to minimize the environmental influences on "path loss". Similarly, in the case of time-varying SAR measurements in Sub6 NR (with LTE as anchor), "path loss" between callbox antenna and the EUT needs to be carefully calibrated for both LTE link as well as for Sub6 NR link.

The DUT is placed in worst-case position according to Table 8-2.

FCC ID: A3LSMT978U	PCTEST [®] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 28 of 86
© 2020 PCTEST		·		REV 1.0

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7 **MEASUREMENT TEST SETUP (FREQ > 6 GHZ)**

7.1 **Radiated Power Measurement Test setup**

The Keysight Technologies E7515B UXM callbox is used in this test. The schematic of the setup is shown in Figure 7-1. The UXM callbox has two RF radio heads to up/down convert IF to mmW frequencies, which in turn are connected to two horn antennas for V- and H-polarizations for downlink communication. In the uplink, a directional coupler is used in the path of one of the horn antennas to measure and record radiated power using a Rohde & Schwarz NRP50S power sensor. Note here that the isolation of the directional coupler may not be sufficient to attenuate the downlink signal from the callbox, which will result in high noise floor masking the recording of radiated power from EUT. In that case, either lower the downlink signal strength emanating from the RF radio heads of callbox or add an attenuator between callbox radio heads and directional coupler. Additionally, note that since the measurements performed in this validation are all relative, measurement of EUT's radiated power in one polarization is sufficient. The EUT is placed inside an anechoic chamber with V- and H-pol horn antennas to establish the radio link as shown in Figure 7-1. The callbox's LTE port is directly connected to the EUT's RF port via a directional coupler to measure the EUT's conducted Tx power using a Rohde & Schwarz NRP8S power sensor. Additionally, EUT is connected to the PC via USB connection for sending beam switch command. Care is taken to route the USB cable and RF cable (for LTE connection) away from the EUT's mmW antenna modules.

Setup in Figure 7-1 is used for the test scenario 1, 5 and 6 described in Section 3. The test procedures described in Section 5 are followed. The path losses from the EUT to both the power meters are calibrated and used as offset in the power meter.

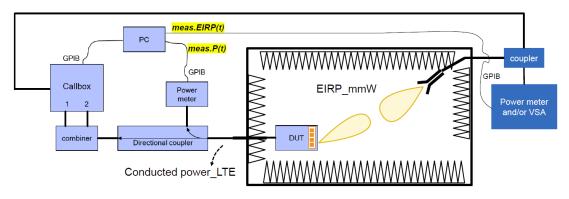


Figure 7-1 mmW NR radiated power measurement setup - Test Setup Photo 7

Both the callbox and power meters are connected to the PC using USB cables. Test scripts are custom made for automation of establishing LTE + mmW call, conducted Tx power recording for LTE and radiated Tx power recording for mmW. These tests are manually stopped after desired time duration. Test script is programmed to set LTE Tx power to all-down bits on the callbox immediately after the mmW link is established, and programmed to set toggle between all-up and all-down bits depending on the transmission scenario being evaluated. Similarly, test script is also programmed to send beam switch command manually to the EUT via USB connection. For all the tests, the callbox is set to request maximum Tx power in mmW NR radio from EUT all the time.

Test configurations for this validation are detailed in Section 5.2. Test procedures are listed in Section 5.3.

FCC ID: A3LSMT978U	Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 29 of 86
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7.2 Power Density Measurement Test setup

The measurement setup is similar to normal PD measurements, the EUT is positioned on cDASY6 platform, and is connected with the callbox (conducted for LTE and wirelessly for mmW). Keysight UXM callbox is set to request maximum mmW Tx power from EUT all the time. Hence, "path loss" calibration between callbox antenna and EUT is not needed in this test. The callbox's LTE port is directly connected to the EUT's RF port via a directional coupler to measure the EUT's conducted Tx power using a Rohde & Schwarz NRP8S power sensor. Additionally, EUT is connected to the PC via USB connection for toggling between FTM and online mode with Smart Transmit enabled following the test procedures described Section 5.4.

Worst-surface of EUT (for the mmW beam being tested) is positioned facing up for PD measurement with cDASY6 mmW probe. Figure 7-2 shows the schematic of this measurement setup.

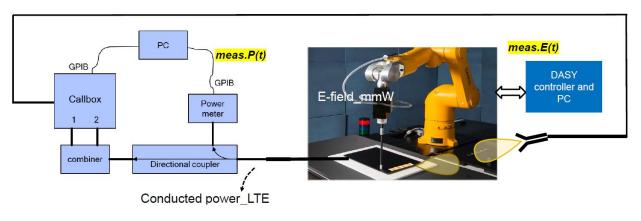


Figure 7-2 Power Density Measurement Setup – Test Setup Photo 6

Both callbox and power meters are connected to the PC using USB cables. Test scripts are custom made for automation of establishing LTE + mmW call, and for conducted Tx power recording of LTE transmission. These tests are manually stopped after desired time duration. Once the mmW link is established, LTE Tx power is programmed to toggle between all-up and all-down bits on the callbox. For all the tests, the callbox is set to request maximum Tx power in mmW NR radio from EUT all the time. Therefore, the calibration for the pathloss between the EUT and the horn antenna connected to the remote radio head of the callbox is not required.

Power meter readings are periodically recorded every 10ms on NR8S power sensor for LTE conducted Tx power. Time-averaged E-field measurements are performed using EUmmWV3 mmW probe at peak location of fast area scan. The distance between EUmmWV3 mmW probe tip to EUT surface is ~0.5 mm. and the distance between EUmmWV3 mmW probe sensor to probe tip is 1.5 mm. cDASY6 records $[pointE(t)]^2$ relative point E-field (i.e., ratio $\frac{|pointE(t)|^2}{[pointE_{input.power.limit]^2}}$) versus time for mmW NR transmission.

FCC ID: A3LSMT978U	Froud to be part of element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 30 of 86
2020 PCTEST				REV 1 (

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8 TEST CONFIGURATIONS (FREQ < 6 GHZ)

8.1 WWAN (sub-6) transmission

The P_{limit} values, corresponding to 1.0 W/kg (1gSAR) and 2.5 W/kg (10gSAR) of SAR_design_target , for technologies and bands supported by DUT are derived in Part 0 report and summarized in Table 8-1. Note all P_{limit} power levels entered in Table 8-1 correspond to average power levels after accounting for duty cycle in the case of TDD modulation schemes.

Exposure Scenario:	Body 1g SAR at Max Power	Body 1g SAR at Reduced Power (Grip 2+3)		Body 1g SAR at Reduced Power (Grip 2)	Maximum Tune-up				
		(- /		······ · · (- - /	Output Power*				
Averaging Volume:	1g	1g	1g	1g	o acput : o me.				
DSI:	0	1	2	3					
Technology/Band	Pl	limit corresponding to 1m	mit corresponding to 1mW/g (SAR_design_target)						
UMTS B5	29.4	17.5	29.4	17.5	24.0				
UMTS B4	26.7	13.5	21.0	13.5	24.0				
UMTS B2	27.3	12.0	21.0	12.0	24.0				
LTE FDD B71	30.7	14.0	30.7	14.0	24.0				
LTE FDD B12	30.0	16.0	30.0	16.0	24.0				
LTE FDD B13	28.2	16.0	28.2	16.0	24.0				
LTE FDD B26	28.8	16.0	26.8	16.0	24.0				
LTE FDD B5	28.8	16.0	28.8	16.0	24.0				
LTE FDD B66/4	26.1	12.5	26.1	12.5	24.0				
LTE FDD B25/2	26.9	12.5	21.0	12.5	24.0				
LTE FDD B7	30.1	12.5	12.5	12.5	24.0				
LTE TDD B41 PC3	29.4	12.0	12.0	12.0	22.0				
LTE TDD B41 PC2	29.4	12.0	12.0	15.6	23.4				
NR FDD n71	30.2	14.0	30.2	14.0	24.0				
NR FDD n5	29.0	16.0	29.0	16.0	24.0				
NR FDD n66	27.3	12.5	27.3	12.5	24.0				
NR FDD n25/2	27.5	12.5	27.5	12.5	24.0				
NR TDD n41	28.1	8.0	8.0	28.1	18.0				

 Table 8-1

 *P*_{limit} for supported technologies and bands (*P*_{limit} in EFS file)

* Maximum tune up target power, P_{max} , is configured in NV settings in DUT to limit maximum transmitting power. This power is converted into peak power in NV settings for TDD schemes. The DUT maximum allowed output power is equal to P_{max} + 1 dB device uncertainty.

Based on selection criteria described in Section 4.2.1, the selected technologies/bands for testing time-varying test sequences are highlighted in yellow in Table 8-1. Per the manufacturer, the *Reserve_power_margin* (dB) is set to 3dB in EFS and is used in Part 2 test.

The radio configurations used in Part 2 test for selected technologies, bands, DSIs and antennas are listed in Table 8-2. The corresponding worst-case radio configuration 1gSAR values for selected technology/band/DSI are extracted from Part 1 report and are listed in the last column of Table 8-2.

Based on equations (1a), (2a), (3a) and (4a), it is clear that Part 2 testing outcome is normalized quantity, which implies that it can be applied to any radio configuration within a selected technology/band/DSI. Thus, as long as applying the worst-case SAR obtained from the worst radio configuration in Part 1 testing to calculate time-varying SAR exposure in equations (1a),

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:	Dama 24 of 20
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet	Page 31 of 86
6	2020 DOTEST			PEV 10

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(2a), (3a) and (4a), the accuracy in compliance demonstration remains the same. Therefore. there may be some differences between the radio configuration selected for Part 2 testing and the radio configuration associated with worst-case SAR obtained in the Part 1 evaluation.

Test Case #	Test Scenario	Tech	Band	Antenna	DSI	Channel	Frequency [MHz]	RB/RB Offset/Bandwidth (MHz)	Mode	SAR Exposure Scenario	Part 1 Worst Case Measured SAR at Plimit (W/kg)									
1	Test Sequence 1		B25	1	2	26365	1882.5	1/50/20 MHz BW	QPSK	grip 3, right edge, 0 mm	0.267									
	Test Sequence 2	LTE	D25		2	26365	1882.5	1/50/20 MHz BW	QPSK	gip 3, fight edge, 0 film	0.207									
2	Test Sequence 1		B41	1	3	40620	2593	1/0/20 MHz BW	QPSK	grip 2, top, 0 mm	0.447									
2	Test Sequence 2		D41	1	3	40620	2593	1/0/20 MHz BW	QPSK	grip 2, top, 0 min	0.447									
3	Test Sequence 1		B5	1	3	4183	836.5	-	RMC	grip 2, top, 0 mm	0.693									
3	Test Sequence 2	UMTS	5		5	4183	836.5	-	RMC	grip 2, top, 0 mm	0.055									
4	Test Sequence 1		011110	B2	1	2	9400	1880	-	RMC	grip 3, right edge, 0 mm	0.274								
-	Test Sequence 2		02		52	52	52	52	52	52	52	02	52	'	2	9400	1880	-	RMC	gip 3, fight edge, 0 film
5	Test Sequence 1	Sub6 NR	n66	1	3	349092	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	grip 2, top, 0 mm	0.544									
	Test Sequence 2			1100	100	100	100	1100	1100		'	5	349092	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	grip 2, top, o min	0.544		
6	Test Sequence 1		SUDO INK	Subo NR	SUDO INK	SUDO INK	SUDO INK	SUDO INK	SUDO NK	Subo Nix	SUDU NIK	SUDO INR	n5	1	3	167300	836.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	grip 2, top, 0 mm
v	Test Sequence 2		10		5	167300	836.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	grip 2, top, o min	0.327									
7	Change in Call	LTE	B41	1	3	40620	2593	1/0/20 MHz BW	QPSK	grip 2, top, 0 mm	0.447									
8	Tech/Band Switch	LTE	B13	1	3	23230	782	1/25/10 MHz BW	QPSK	grip 2, back, 0 mm	0.453									
0	Tech/Band Switch	UMTS	B2	1	3	9400	1880	-	RMC	grip 2, top, 0 mm	0.602									
9	DSI Switch	UMTS	B2	1	3	9400	1880	-	RMC	grip 2, top, 0 mm	0.602									
9	DSI SWITCH	UNIS	UNIS	UNIS	UVIIS	UNIS	UNIS	UNIS	UNIS	UNIS	UNIS	ΒZ	1	2	9400	1880	-	RMC	grip 3, right edge, 0 mm	0.274
10	SAR1 vs SAR2	LTE	B5	1	3	20525	836.5	1/25/10 MHz BW	QPSK	grip 2, back, 0 mm	0.393									
10	UNIT VS UNITZ	sub6 NR	n66	1	3	349092	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	grip 2, top, 0 mm	0.544									

Table 8-2 Radio configurations selected for Part 2 test

Note: Antenna switch test case was not included in the test plan selection since the DUT does not support any SA transmission on any additional antennas.

Table 8-3
DSI and Corresponding Exposure Scenarios

Scenario	Description	SAR Test Cases
Grip Sensor 3 Active (DSI = 2)	 Device is within certain distance of user. Grip Sensor #3 is triggered. Grip Sensor #3 is collocated with WIFI Ant1 antenna 	Tablet SAR per KDB Publication 616217 D04
Grip Sensor 2 Active (DSI = 3)	 Device is within certain distance of user. Grip Sensor #2 is triggered. Grip Sensor #2 is collocated with Main 1 antenna 	Tablet SAR per KDB Publication 616217 D04
Grip Sensor 2 and 3 Active (DSI=1)	 Device is within certain distance of user. Grip sensor #2 and #3 are triggered. Grip Sensor #3 is collocated with WIFI Ant1 antenna. Grip Sensor #2 is collocated with Main 1 antenna. 	Tablet SAR per KDB Publication 616217 D04
Free Space (DSI = 0)	Device not close to user.Grip sensors are not triggered	Tablet SAR per KDB Publication 616217 D04

Based on the selection criteria described in Section 4.2, the radio configurations for the Tx varying transmission test cases listed in Section 3 are:

- 1. <u>Technologies and bands for time-varying Tx power transmission</u>: The test case 1~6 listed in Table 8-2 are selected to test with the test sequences defined in Section 4.1 in both timevarying conducted power measurement and time-varying SAR measurement.
- 2. Technology and band for change in call test: LTE Band 41, having the lowest Plimit among all technologies and bands (test case 7 in Table 8-2), is selected for performing the call drop test in conducted power setup.

04/06/2020

FCC ID: A3LSMT978U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager		
Document S/N:	Test Dates:	DUT Type:		Dage 22 of 96		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 32 of 86		
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- Technologies and bands for change in technology/band test: Following the guidelines in Section 4.2.3, test case 8 in Table 8-2 is selected for handover test from a technology/band within one technology group (LTE Band 13, DSI=3, antenna 1), to a technology/band in the same DSI within another technology group (UMTS B2, DSI=3, antenna 1) in conducted power setup.
- 4. Technologies and bands for change in DSI: Based on selection criteria in Section 4.2.5, for a given technology and band, test case 9 in Table 8-2 is selected for DSI switch test by establishing a call in UMTS Band 2 in DSI=3, and then handing over to DSI = 2 exposure scenario in conducted power setup.
- 5. Technologies and bands for switch in SAR exposure: Based on selection criteria in Section 4.2.7 Scenario 1, test case 10 in Table 8-2 is selected for SAR exposure switching test in one of the supported simultaneous WWAN transmission scenario, i.e., LTE + Sub6 NR active in the same 100s time window, in conducted power setup. Since this device supports LTE+mmW NR, test for Section 4.2.7 Scenario 2 for RF exposure switch is covered in Sections 13.1 and 13.2 between LTE (100s window) and mmW NR (4s window).

8.2 *P*_{limit} and *P*_{max} measurement results

The measured Plimit for all the selected radio configurations given in Table 8-2 are listed in below Table 8-3. P_{max} was also measured for radio configurations selected for testing time-varying Tx power transmission scenarios in order to generate test sequences following the test procedures in Section 4.1.

Test Case #	Test Scenario	Tech	Band	Antenna	DSI	Channel	Frequency [MHz]	RB/RB Offset/Bandwidth (MHz)	Mode	SAR Exposure Scenario	EFS Plimit [dBm]	Tune-up Pmax [dBm]	Measured Plimit [dBm]	Measured Pmax [dBm]
1	Test Sequence 1		B25	1	2	26365	1882.5	1/50/20 MHz BW	QPSK	Grip 3	21	24	21.13	24.12
' '	Test Sequence 2	LTE	DZD		2	26365	1882.5	1/50/20 MHz BW	QPSK	Gilp 5	21	24	21.13	24.12
2	Test Sequence 1	LIE	B41	1	3	40620	2593	1/0/20 MHz BW	QPSK	Grip 2	12	22	11.3	22.15
4	Test Sequence 2		D41		3	40620	2593	1/0/20 MHz BW	QPSK	Grip 2	12	22	11.3	22.15
3	Test Sequence 1		B5	1	3	4183	836.5	-	RMC	Grip 2	17.5	24	18.14	23.93
3	Test Sequence 2	UMTS	BO	'	3	4183	836.5	-	RMC	Grip 2	17.5	24	18.14	23.93
4	Test Sequence 1	UNIS	B2	4	2	9400	1880	-	RMC	Grip 3	21	24	21.46	23.97
-	Test Sequence 2		02		2	9400	1880	-	RMC	Onp 5	21	24	21.46	23.97
5	Test Sequence 1		n66	1	3	349092	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Grip 2	12.5	24	12.66	24.23
5	Test Sequence 2	Sub6 NR	100		3	349092	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Grip 2	12.5	24	12.66	24.23
6	Test Sequence 1	SUDO INR	n5	4	3	167300	836.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Onin O	16	24	15.35	24.29
°	Test Sequence 2	1	cn	'	3	167300	836.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Grip 2	16	24	15.35	24.29
7	Change in Call	LTE	B41	1	3	40620	2593	1/0/20 MHz BW	QPSK	Grip 2	12	22	11.3	22.15
_	To L (Data L O Hall	LTE	B13	1	3	23230	782	1/25/10 MHz BW	QPSK	Grip 2	16	24	16.75	24.47
8	Tech/Band Switch	UMTS	B2	1	3	9400	1880	-	RMC	Grip 2	12	24	12.91	24.41
				1	3	9400	1880	-	RMC	Grip 2	12	24	12.91	24.41
9	DSI Switch	UMTS	B2	1	2	9400	1880	-	RMC	Grip 3	21	24	21.46	23.97
		LTE	B5	1	3	20525	836.5	1/25/10 MHz BW	QPSK	Grip 2	16	24	16.01	24.01
10	SAR1 vs SAR2	sub6 NR	n66	1	3	349092	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Grip 2	12.5	24	12.66	24.23

Table 8-4 Measured Plimit and Pmax of selected radio configurations

Note: The device uncertainty of P_{max} is +/- 1 dB as provided by manufacturer.

FCC ID: A3LSMT978U	Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager		
Document S/N:	Test Dates:	DUT Type:				
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 33 of 86		
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9 CONDUCTED TX CASES (FREQ < 6 GHZ)

FCC SAR limit

9.1 **Time-varying Tx Power Case**

The measurement setup is shown in Figure 6-1. The purpose of the time-varying Tx power measurement is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged Tx power when represented in time-averaged 1gSAR or 10gSAR values does not exceed FCC limit as shown in Eq. (1a) and (1b), rewritten below:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(1a)
$$\frac{\frac{1}{T_{SAR}}\int_{t=T_{SAR}}^{t} 1g_or_10gSAR(t)dt}{\frac{1}{T_{SAR}}\int_{t=T_{SAR}}^{t} 1g_or_10gSAR(t)dt} \leq 1$$
(1b)

where, $conducted_Tx_power(t)$, $conducted_Tx_power_P_{limit}$, and $1g_or_10gSAR_P_{limit}$ correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at Plimit, and measured 1gSAR and 10gSAR values at Plimit reported in Part 1 test (listed in Table 8-2 of this report as well).

Following the test procedure in Section 4.3, the conducted Tx power measurement for all selected configurations are reported in this section. In all the conducted Tx power plots, the dotted line represents the requested power by callbox (test sequence 1 or test sequence 2), the blue curve represents the instantaneous conducted Tx power measured using power meter, the green curve represents time-averaged power and red line represents the conducted power limit that corresponds to FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

Similarly, in all the 1g or 10gSAR plots (when converted using Eq. (1a)), the green curve represents the 100s/60s-time averaged 1gSAR or 10gSAR value calculated based on instantaneous 1gSAR or 10gSAR; and the red line limit represents the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

Time-varying Tx power measurements were conducted on test cases $\#1 \sim \#6$ in Table 8-2, by generating test sequence 1 and test sequence 2 given in APPENDIX E: using measured Plimit and measured Pmax (last two columns of Table 8-3) for each of these test cases. Measurement results for test cases $#1 \sim #6$ are given in Sections 9.1.1-9.1.7.

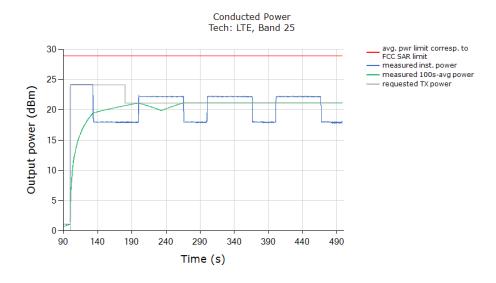
FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 34 of 86
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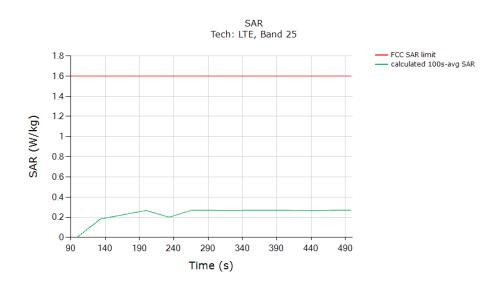
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Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

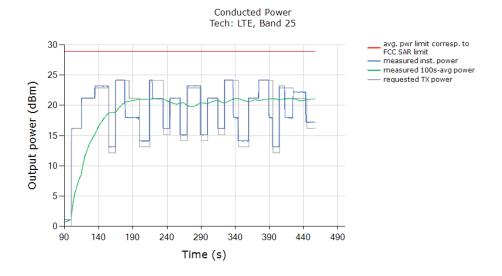


	(W/kg)				
FCC 1gSAR limit	1.6				
Max 100s-time averaged 1gSAR (green curve)	0.269				
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).					

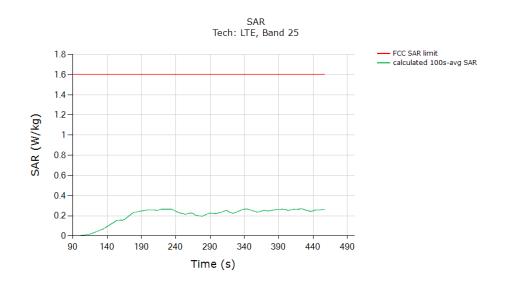
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	Document S/N:	Test Dates:	DUT Type:		Dage 25 of 96
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 35 of 86
0	2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



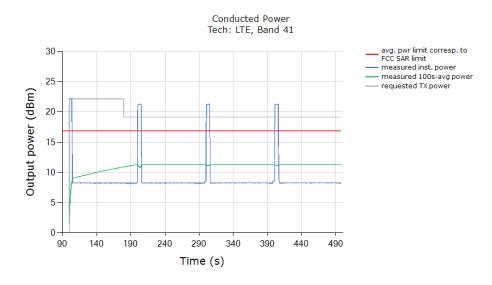
	(W/kg)					
FCC 1gSAR limit	1.6					
Max 100s-time averaged 1gSAR (green curve)	0.267					
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).						

FCC ID: A3LSMT978U	Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 36 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
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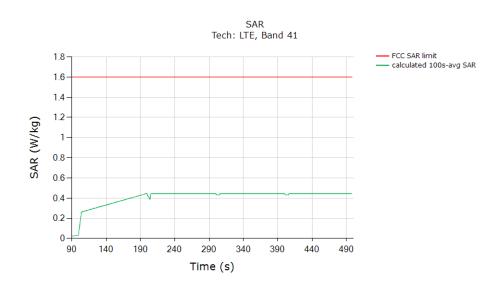
REV 1.0 04/06/2020



Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

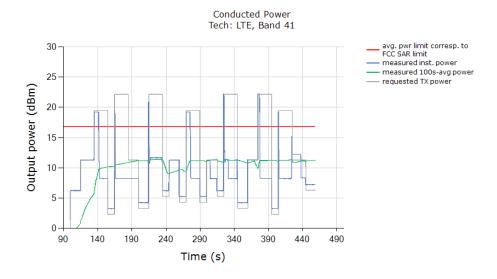


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.445
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

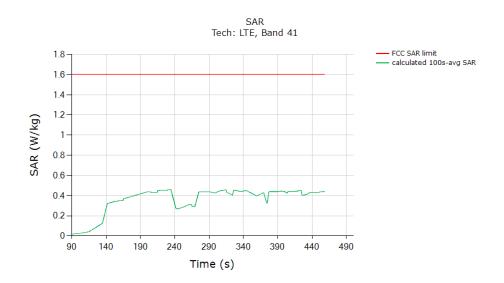
FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 27 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 37 of 86
© 2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



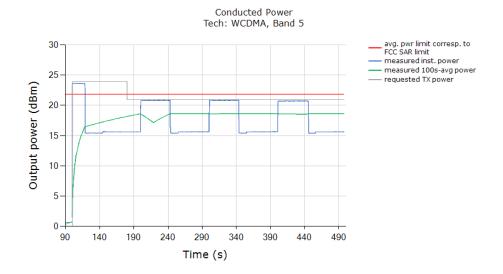
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.457
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 29 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 38 of 86
© 2020 PCTEST				REV 1.0

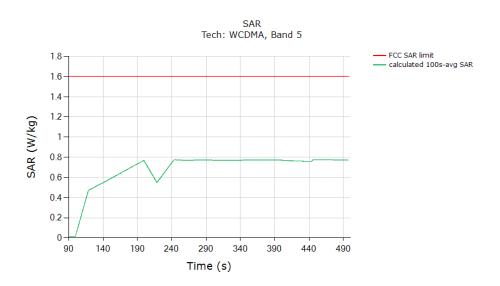
REV 1.0 04/06/2020

9.1.3 **UMTS B5**

Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

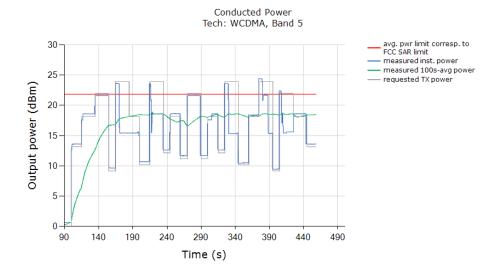


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.772
Validated: Max time averaged SAR (green curve) is within 1 dB device uncerta SAR at <i>P</i> _{limit} (last column in Table 8-2).	ainty of measured

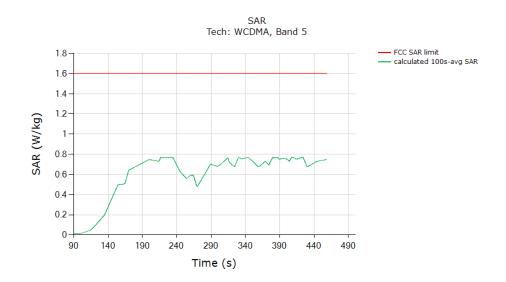
	FCC ID: A3LSMT978U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 20 of 96
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 39 of 86
6	2020 DOTEST				PEV 10

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Test result for test sequence 2:



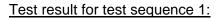
Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

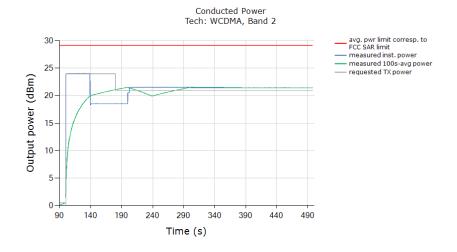


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.770
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

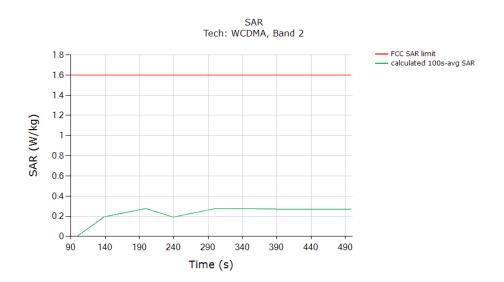
FCC ID: A3LSMT978U	PCTEST Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		D 10 (00	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 40 of 86	
© 2020 PCTEST				REV 1.0 04/06/2020	

9.1.4 **UMTS B2**





Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

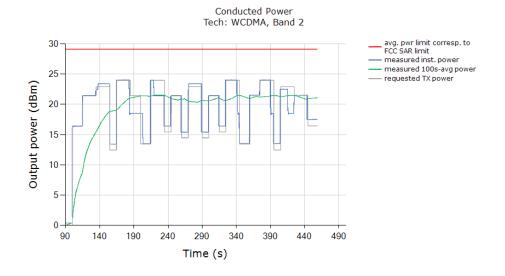


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.276
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> _{limit} (last column in Table 8-2).	ty of measured

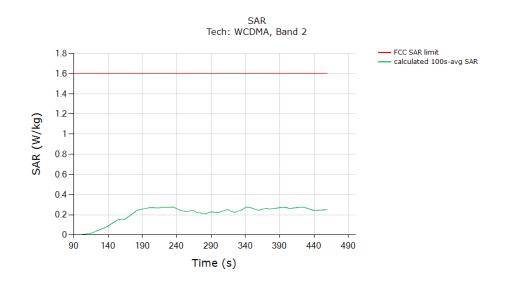
FCC ID: A3LSMT978U	PCTEST* Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 41 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 41 of 86
© 2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

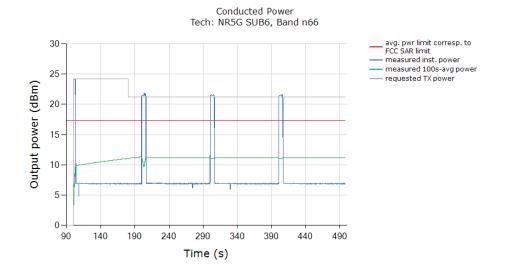


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.276
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	ty of measured

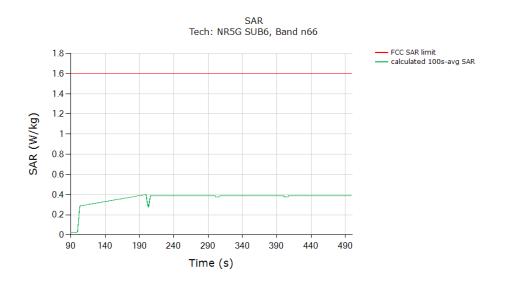
FCC ID: A3LSMT978U	Proved to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		D
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 42 of 86
© 2020 PCTEST				REV 1.0 04/06/2020

NR n66 9.1.5

Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

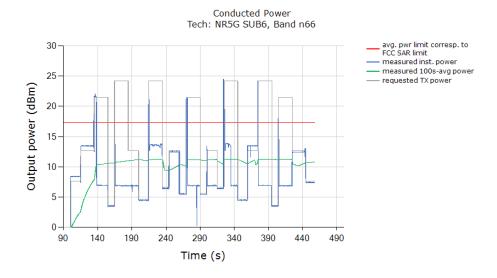


	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged 1gSAR (green curve)	0.400			
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).				

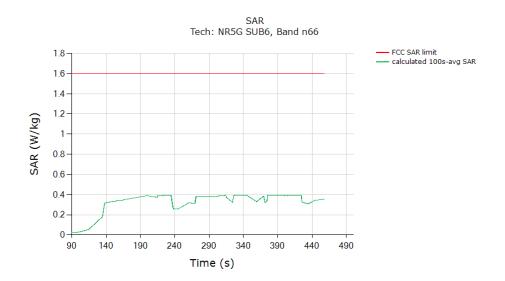
	FCC ID: A3LSMT978U	PCTEST [•] Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dama 40 at 00
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 43 of 86
C	2020 PCTEST				REV 1.0

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Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

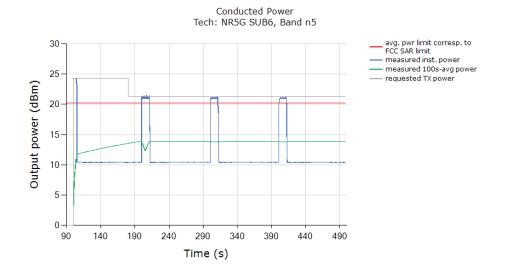


	(W/kg)		
FCC 1gSAR limit	1.6		
Max 100s-time averaged 1gSAR (green curve)	0.395		
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).			

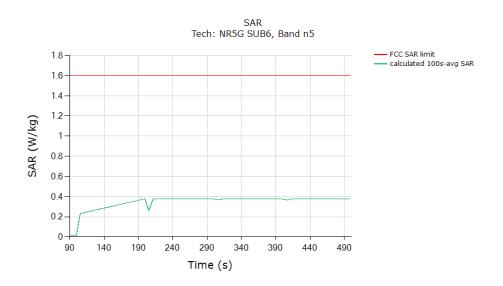
FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 44 of 86
© 2020 PCTEST				REV 1.0 04/06/2020

9.1.6 **NR n5**

Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

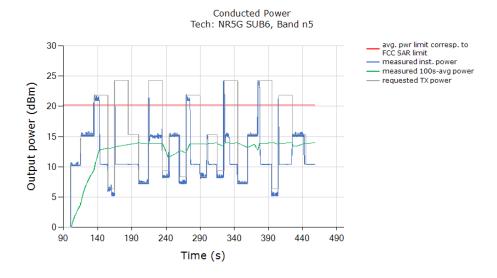


	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged 1gSAR (green curve)	0.378			
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).				

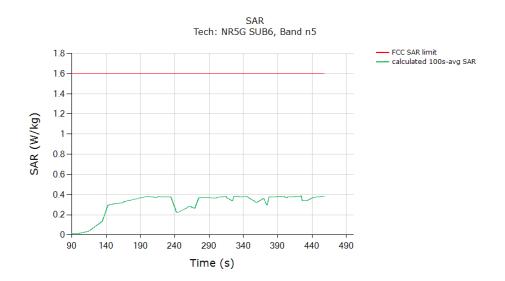
	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 45 of 96
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 45 of 86
G	2020 DCTEST				DEV/10

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Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



	(W/kg)		
FCC 1gSAR limit	1.6		
Max 100s-time averaged 1gSAR (green curve)	0.385		
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB Reserve_power_margin setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).			

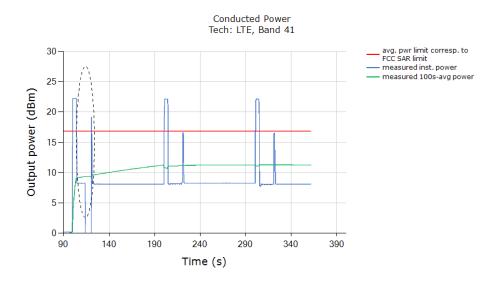
FCC ID: A3LSMT978U	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		D
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 46 of 86
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9.2 Call Drop Test Case

This test was measured LTE Band 41, Antenna 1, DSI=3, and with callbox requesting maximum power. The call drop was manually performed when the DUT is transmitting at $P_{reserve}$ level as shown in the plot below (dotted black region). The measurement setup is shown in Figure 6-1. The detailed test procedure is described in Section 4.3.2.

Call drop test result:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power kept the same $P_{reserve}$ level of LTE Band 41 after the call was re-established:

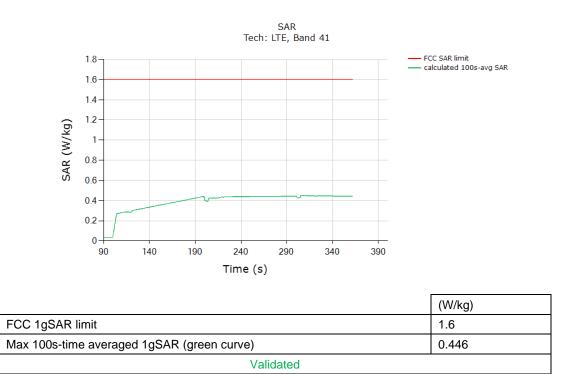


Plot Notes: The power level after the change in call kept the same *P*_{reserve} level of LTE Band 41. The conducted power plot shows expected Tx transition.

Plot 2: Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 47 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
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REV 1.0 04/06/2020



The test result validated the continuity of power limiting in call change scenario.

9.3 Change in Technology/Band Test Case

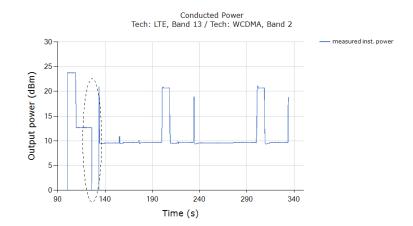
This test was conducted with callbox requesting maximum power, and with a technology switch from LTE 13, Antenna 1, DSI = 3 to UMTS B2, Antenna 1, DSI = 3. Following procedure detailed in Section 4.3.3, and using the measurement setup shown in Figure 6-1, the technology/band switch was performed when the DUT is transmitting at *P*_{reserve} level as shown in the plot below (dotted black region).

Test result for change in technology/band:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed from LTE 13, Antenna 1, DSI = 3 Preserve level to UMTS B2, Antenna 1, DSI = 3 Preserve level (within 1 dB device uncertainty):

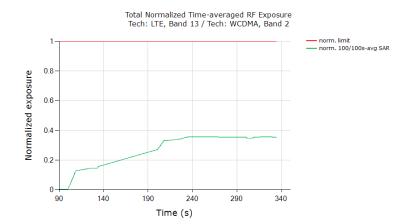
FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		D
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 48 of 86
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Note: As per the manufacturer, *Reserve_power_margin* = 3 dB. Based on Table 8-1, EFS *Plimit* = 16dBm for LTE B13 (DSI=3), and EFS *Plimit* = 12dBm for UMTS B2 (DSI=3), it can be seen from above plot that the difference in *Preserve* (= *Plimit* – *3dB Reserve_power_margin*) power level corresponds to the expected difference in *Plimit* levels of 4 dB (within 1dB of sub6 radio design related uncertainty). Therefore, the conducted power plot shows expected transition in Tx power.

Plot 2: All the time-averaged conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (6a), (6b) and (6c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the normalized FCC limit of 1.0:



	(W/kg)
FCC normalized SAR limit	1.0
Max 100s-time averaged normalized SAR (green curve)	0.356
Validated	

The test result validated the continuity of power limiting in technology/band switch scenario.

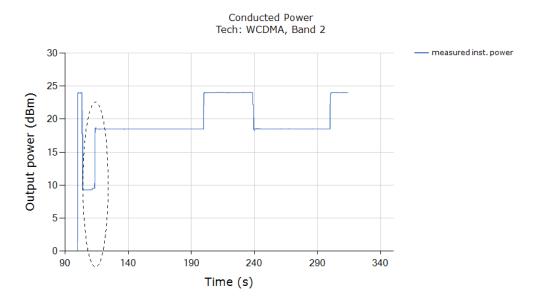
FCC ID: A3LSMT978U	PCTEST* Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 40 af 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 49 of 86
© 2020 PCTEST				REV 1.0 04/06/2020

9.4 DSI Switch Test Case

This test was conducted with callbox requesting maximum power, and with DSI switch from UMTS Band 2 DSI = 3 (grip 2 sensor triggered) to DSI = 2 (grip 3 sensor triggered). Following procedure detailed in Section 4.3.5 using the measurement setup shown in Figure 6-1, the DSI switch was performed when the DUT is transmitting at $P_{reserve}$ level as shown in the plot below (dotted black circle).

Test result for change in DSI:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed when DSI = 3 switches to DSI = 2:

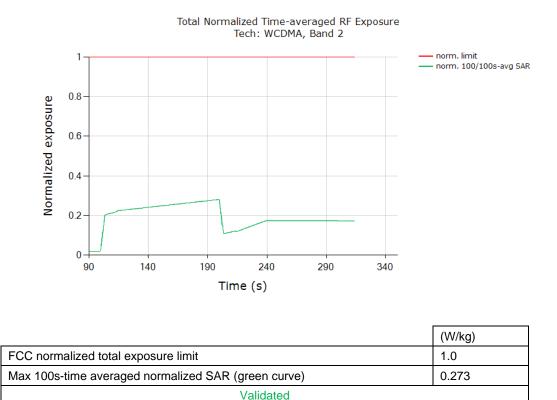


Note: As per the manufacturer, *Reserve_power_margin* = 3dB. Based on Table 8-1, EFS *Plimit* = 12 dBm for UMTS Band 2 Grip2 DSI = 3, and EFS *Plimit* = 21.0 dBm for Grip3 DSI = 1.The difference in *Preserve* (= *Plimit* – 3dB Reserve_power_margin) level corresponds to the expected different in *Plimit* levels of 9 dB (within 1dB of sub6 radio design related uncertainty). Therefore, the conducted power plot shows expected transition in Tx power.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager			
Document S/N:	Test Dates:	DUT Type:		Daga 50 of 90			
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 50 of 86			
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REV 1.0 04/06/2020

Plot 2: All the time-averaged conducted Tx power measurement results were converted into timeaveraged normalized SAR values using Equation (6a), (6b) and (6c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the FCC limit of 1 unit.



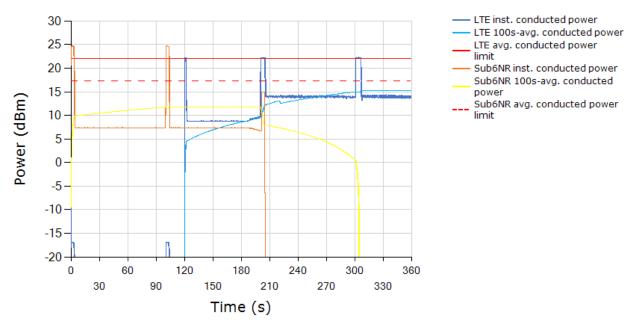
The test result validated the continuity of power limiting in DSI switch scenario.

9.5 Switch in SAR exposure test results

This test was conducted with callbox requesting maximum power, and with the EUT in LTE B5 + Sub6 NR Band n66 call. Following procedure detailed in Section 4.3.7 and Appendix F.2, and using the measurement setup shown in Figure 6-1(c) since LTE and Sub6 NR are sharing the same antenna port, the SAR exposure switch measurement is performed with the EUT in various SAR exposure scenarios, i.e., in SAR_{sub6NR} only scenario (t =0s ~120s), SAR_{su6NR} + SAR_{LTE} scenario (t =120s ~ 240s) and SAR_{LTE} only scenario (t > 240s).

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 51 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 51 of 86
© 2020 PCTEST				REV 1.0

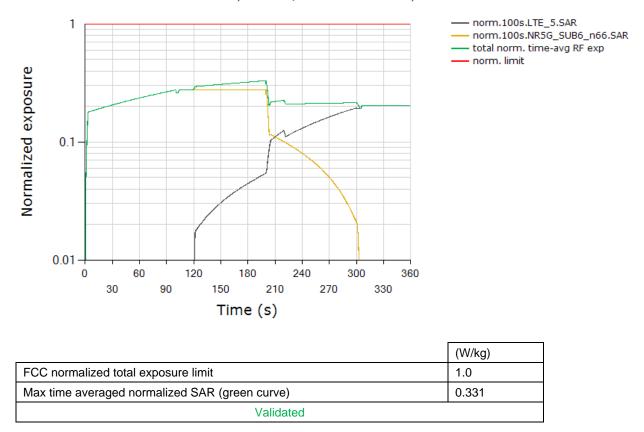
REV 1.0 04/06/2020



LTE and mmW Instantaneous and Time-averaged TX Power Tech: LTE, Band 5 / Tech: NR5G SUB6, Band n66

Plot 2: All the conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (7a), (7b) and (7c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the FCC limit of 1 unit. Equation (7a) is used to convert the LTE Tx power of device to obtain 100s-averaged normalized SAR in LTE B5 as shown in black curve. Similarly, equation (7b) is used to obtain 100s-averaged normalized SAR in Sub6 NR n66 as shown in orange curve. Equation (7c) is used to obtain total time-averaged normalized SAR as shown in green curve (i.e., sum of black and orange curves).

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 52 of 86
© 2020 PCTEST				REV 1.0



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 5 / Tech: NR5G SUB6, Band n66

Plot Notes: Device starts predominantly in Sub6 NR SAR exposure scenario between 0s and 120s, and in LTE SAR + Sub6 NR SAR exposure scenario between 120s and 240s, and in predominantly in LTE SAR exposure scenario after t=240s. Here, Smart Transmit allocates a maximum of 75% of exposure margin (based on 3dB reserve margin setting) for Sub6 NR. This corresponds to a normalized 1gSAR exposure value = 75% * 0.544 W/kg measured SAR at Sub6 NR *Plimit* / 1.6W/kg limit = $0.255 \pm 1dB$ device related uncertainty (see orange curve between 0s~120s). For predominantly LTE SAR exposure scenario, maximum normalized 1gSAR exposure should correspond to 100% exposure margin = 0.393 W/kg measured SAR at LTE Plimit / 1.6W/kg limit = $0.246 \pm 1dB$ device related uncertainty (see black curve after t = 240s). Additionally, in SAR exposure switch test, at all times the total time-averaged normalized RF exposure (green curve) should not exceed normalized SAR design target + 1dB device uncertainty. In this test, with a maximum normalized SAR of 0.331 being \leq 0.79 (= 1.0/1.6 + 1dB device uncertainty), the above test result validated the continuity of power limiting in SAR exposure switch scenario.

FCC ID: A3LSMT978U	PCTEST [®] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 52 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 53 of 86
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04/06/2020

10 SYSTEM VERIFICATION (FREQ < 6 GHZ)

Tissue Verification 10.1

Calibrated for Tests Performed on:	Tissue Type	Tissue Temp During Calibration (°C)	Measured Frequency (MHz)	Measured Conductivity, σ (S/m)	Measured Dielectric Constant, ε	TARGET Conductivity, σ (S/m)	TARGET Dielectric Constant, ε	% dev σ	% dev ε
			820	0.983	54.922	0.969	55.258	1.44%	-0.61%
07/21/2020	835 Body	22.3	835	0.989	54.877	0.970	55.200	1.96%	-0.59%
			850	0.996	54.834	0.988	55.154	0.81%	-0.58%
			820	0.975	55.081	0.969	55.258	0.62%	-0.32%
07/23/2020	835 Body	22	835	0.980	55.058	0.970	55.200	1.03%	-0.26%
			850	0.988	55.021	0.988	55.154	0.00%	-0.24%
			1710	1.454	54.245	1.463	53.537	-0.62%	1.32%
			1720	1.460	54.212	1.469	53.511	-0.61%	1.31%
07/00/0000	4750 Deate	01	1745	1.478	54.167	1.485	53.445	-0.47%	1.35%
07/23/2020	1750 Body	21	1750	1.482	54.157	1.488	53.432	-0.40%	1.36%
			1770	1.496	54.114	1.501	53.379	-0.33%	1.38%
			1790	1.509	54.086	1.514	53.326	-0.33%	1.43%
		900 Body 22.3	1850	1.546	53.163	1.520	53.300	1.71%	-0.26%
	1900 Body		1860	1.553	53.151	1.520	53.300	2.17%	-0.28%
07/04/0000			1880	1.568	53.124	1.520	53.300	3.16%	-0.33%
07/21/2020			1900	1.582	53.103	1.520	53.300	4.08%	-0.37%
			1905	1.586	53.098	1.520	53.300	4.34%	-0.38%
			1910	1.590	53.092	1.520	53.300	4.61%	-0.39%
			1850	1.544	54.456	1.520	53.300	1.58%	2.17%
			1860	1.551	54.441	1.520	53.300	2.04%	2.14%
07/07/0000			1880	1.565	54.415	1.520	53.300	2.96%	2.09%
07/27/2020	1900 Body	21.6	1900	1.580	54.394	1.520	53.300	3.95%	2.05%
			1905	1.583	54.389	1.520	53.300	4.14%	2.04%
			1910	1.587	54.385	1.520	53.300	4.41%	2.04%
			2500	2.073	52.417	2.021	52.636	2.57%	-0.42%
			2510	2.083	52.408	2.035	52.623	2.36%	-0.41%
			2535	2.105	52.374	2.071	52.592	1.64%	-0.41%
07/00/0000		04.0	2550	2.120	52.324	2.092	52.573	1.34%	-0.47%
07/23/2020	2600 Body	21.9	2560	2.128	52.323	2.106	52.560	1.04%	-0.45%
			2600 2650	2.171 2.216	52.265 52.173	2.163 2.234	52.509 52.445	0.37% -0.81%	-0.46% -0.52%
			2650	2.216	52.173	2.234	52.445	-0.81%	-0.52%
			2000	2.247	52.093	2.305	52.382	-1.56%	-0.55%

Table 10-1 **Measured Tissue Properties**

The above measured tissue parameters were used in the DASY software. The DASY software was used to perform interpolation to determine the dielectric parameters at the SAR test device frequencies (per KDB Publication 865664 D01v01r04 and IEEE 1528-2013 6.6.1.2). The tissue parameters listed in the SAR test plots may slightly differ from the table above due to significant digit rounding in the software.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		D
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 54 of 86
© 2020 PCTEST				REV 1.0 04/06/2020

10.2 Test System Verification

Prior to SAR assessment, the system is verified to ±10% of the SAR measurement on the reference dipole at the time of calibration by the calibration facility. Full system validation status and result summary can be found in Appendix C.

	System Verification TARGET & MEASURED											
SAR System #	Tissue Frequency (MHz)	Tissue Type	Date	Amb. Temp (°C)	Liquid Temp (°C)	Input Power (W)	Source SN	Probe SN	Measured SAR _{1g} (W/kg)	1 W Target SAR ^{1g} (W/kg)	1 W Normalized SAR₁g (W/kg)	Deviation _{1g} (%)
М	835	BODY	07/21/2020	21.9	22.3	0.200	4d132	7526	2.010	9.960	10.050	0.90%
М	835	BODY	07/23/2020	22.0	22.0	0.200	4d132	7526	1.820	9.960	9.100	-8.63%
М	1750	BODY	07/23/2020	22.0	21.0	0.100	1150	7526	3.910	36.600	39.100	6.83%
М	1900	BODY	07/21/2020	21.9	22.3	0.100	5d148	7526	4.240	39.100	42.400	8.44%
М	1900	BODY	07/27/2020	22.4	21.6	0.100	5d148	7526	4.010	39.100	40.100	2.56%
М	2600	BODY	07/23/2020	22.0	21.9	0.100	1004	7526	5.250	54.800	52.500	-4.20%

Table 10-2 System Verification Results - 1g

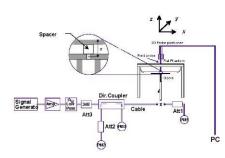


Figure 10-1 System Verification Setup Diagram



Figure 10-2 System Verification Setup Photo

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 55 of 86
© 2020 PCTEST				REV 1.0 04/06/2020

11 SAR TEST RESULTS (FREQ < 6 GHZ)

Time-varying Tx Power Case 11.1

Following Section 4.4 procedure, time-averaged SAR measurements are conducted using a SAR probe at peak location of area scan over 500 seconds. cDASY6 system verification for SAR measurement is provided in Section 10, and the associated SPEAG certificates are attached in Appendix G.

SAR probe integration times depend on the communication signal being tested as defined in the probe calibration parameters.

Since the sampling rate used by cDASY6 for pointSAR measurements is not in user control, the number of points in 100s interval is determined from the scan duration setting in cDASY6 timeaverage pointSAR measurement by (100s cDASY6_scan_duration * total number of pointSAR values recorded). Running average is performed over these number of points in excel spreadsheet to obtain 100s averaged point SAR.

Following Section 4.4, for each of selected technology/band (listed in Table 8-2):

- 6. With Reserve_power_margin set to 0 dB, area scan is performed at Plimit, and time-averaged pointSAR measurements are conducted to determine the pointSAR at P_{limit} at peak location, denoted as *point*SAR_{Plimit}.
- 7. With Reserve_power_margin set to actual (intended) value, two more time-averaged pointSAR measurements are performed at the same peak location for test sequences 1 and 2.

To demonstrate compliance, all the pointSAR measurement results were converted into 1gSAR or 10gSAR values by using Equation (3a), rewritten below:

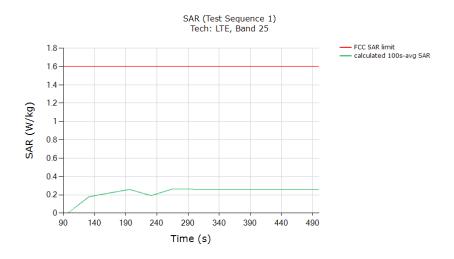
$$1g_or_10gSAR(t) = \frac{pointSAR(t)}{pointSAR_{P_{limit}}} * 1g_or_10gSAR_{P_{limit}}$$
(3a)

where, pointSAR(t), $pointSAR_{limit}$, and $1g_{or}_{10}gSAR_{limit}$ correspond to the measured instantaneous point SAR, measured point SAR at Plimit from above step 1 and 2, and measured 1gSAR or 10gSAR values at Plimit obtained from Part 1 report and listed in Table 8-2 of this report.

FCC ID: A3LSMT978U	Froud to be part of @ element			Approved by: Quality Manager		
Document S/N:	Test Dates:	DUT Type:		Daga 56 of 96		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet	Page 56 of 8			
© 2020 PCTEST				REV 1 (

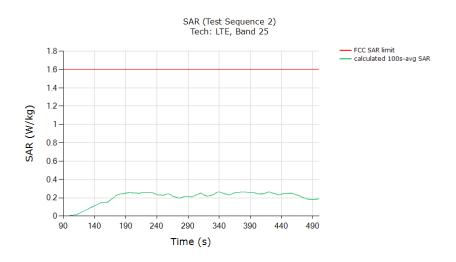
11.1.1 LTE Band 25

SAR test results for test sequence 1:



	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged point 1gSAR (green curve)	0.260			
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).				

SAR test results for test sequence 2:



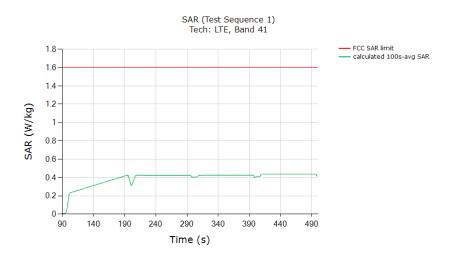
	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged 1gSAR (green curve)	0.262			
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).				

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 57 of 96
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 57 of 86
C	2020 DOTEST				DEV/1/

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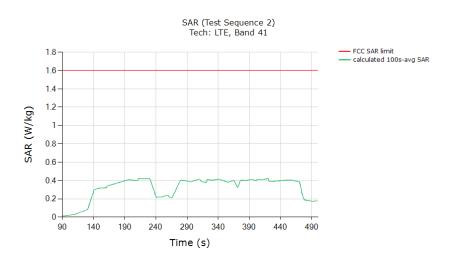
11.1.2 LTE Band 41

SAR test results for test sequence 1:



	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged point 1gSAR (green curve)	0.436	
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).		

SAR test results for test sequence 2:



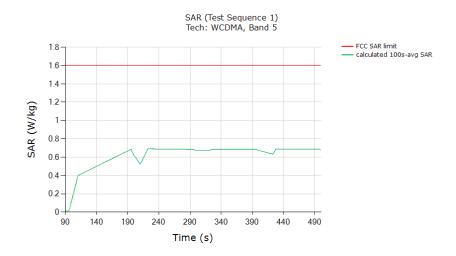
	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.420	
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).		

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
	Document S/N:	Test Dates:	DUT Type:		Dage 59 of 96	
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 58 of 86	
G	2020 DOTEST				DEV/1/	٦

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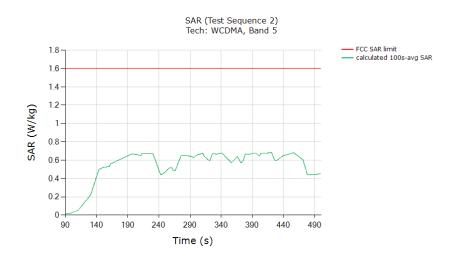
11.1.3 **UMTS B5**

SAR test results for test sequence 1:



	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged point 1gSAR (green curve)	0.690	
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>Plimit</i> (last column in Table 8-2).		

SAR test results for test sequence 2:



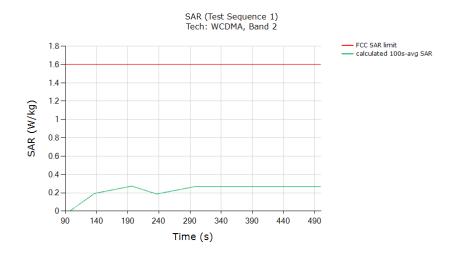
	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.682	
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).		

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAM SUNG	Approved by: Quality Manager	
	Document S/N:	Test Dates:	DUT Type:		Dage 50 of 96	
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 59 of 86	
C	2020 POTEST				DEV/1	

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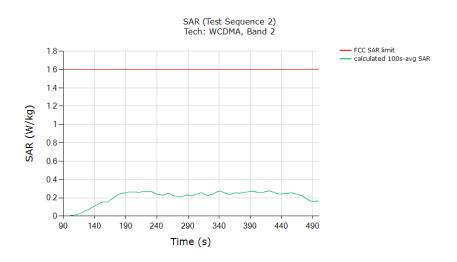
11.1.4 **UMTS B2**

SAR test results for test sequence 1:



	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged point 1gSAR (green curve)	0.272	
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).		

SAR test results for test sequence 2:



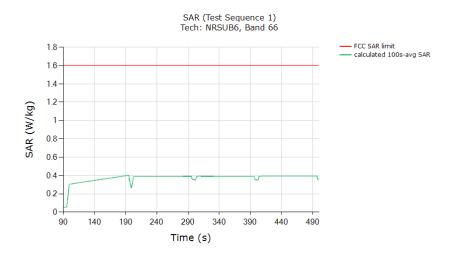
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.273
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).	

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
	Document S/N:	Test Dates:	DUT Type:		Dage 60 of 96	
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 60 of 86	
C	2020 DOTEST				PEV 10	

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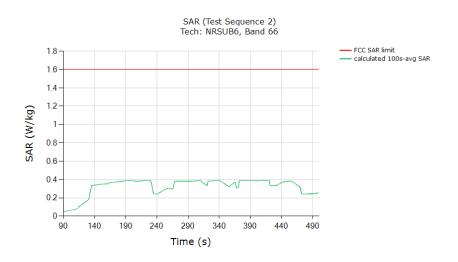
11.1.5 NR n66

SAR test results for test sequence 1:



	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged point 1gSAR (green curve)	0.400	
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).		

SAR test results for test sequence 2:



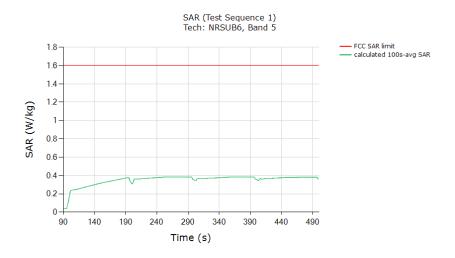
	(W/kg)		
FCC 1gSAR limit	1.6		
Max 100s-time averaged 1gSAR (green curve)	0.390		
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).			

	FCC ID: A3LSMT978U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
	Document S/N:	Test Dates:	DUT Type:		Dage 61 of 96	1
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 61 of 86	
6	2020 PCTEST				REV 1	Λ

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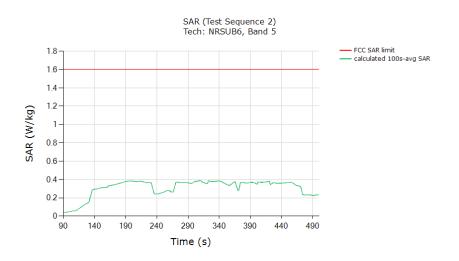
11.1.6 **NR n5**

SAR test results for test sequence 1:



	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged point 1gSAR (green curve)	0.383			
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).				

SAR test results for test sequence 2:



	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged 1gSAR (green curve)	0.387			
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).				

	FCC ID: A3LSMT978U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
	Document S/N:	Test Dates:	DUT Type:		Dage 62 of 86	
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 62 of 86	
6	2020 POTEST				DEV/1	١

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12 TEST CONFIGURATIONS (FREQ > 6 GHZ)

12.1 LTE + mmW NR transmission

Based on the selection criteria described in Section 4.2, the selections for LTE and mmW NR validation test are listed in Table 12-1. The radio configurations used in this test are listed in Table 12-2.

T			
Transmission Scenario	Test	Technology and Band	mmW Beam
Time-varying	1. Cond. & Rad. P	bower LTE Band 2 and n261	Beam ID 24
Tx power test	meas. 2. PD meas.	LTE Band 2 and n260	Beam ID 24
Switch in SAR	1. Cond. & Rad. Power	Ower LTE Band 2 and n261	Beam ID 24
vs. PD	meas.	LTE Band 2 and n260	Beam ID 24
Beam switch test	1. Cond. & Rad. P	Ower LTE Band 2 and n261	Beam ID 24 to Beam ID 0
	meas.	LTE Band 2 and n260	Beam ID 24 to Beam ID 0

 Table 12-1

 Selections for LTE + mmW NR validation measurements

Table 12-2 Test configuration for LTE + mmW NR validation

Tech	Band	Antenna	DSI	Channel	Freq (MHz)	RB/RB Offset/Bandwidth (MHz)	Mode	UL Duty Cycle
LTE	2	0	3	18900	1880	1/0/20 MHz BW	QPSK	100%
	n261	0	-	2071821	27559.32	66/0/100 MHz BW	CP-OFDM, QPSK	75.6%*
mmW NR	n260	0	-	2254147	38498.88	66/0/100 MHz BW	CP-OFDM, QPSK	75.6%*

12.2 mmW NR radiated power test results

To demonstrate the compliance, the conducted Tx power of LTE 2 in DSI = 3 is converted to 1gSAR exposure by applying the corresponding worst-case 1g SAR value at P_{limit} as reported in Part 1 report and listed in Table 8-2 of this report.

Similarly, following Step 4 in Section 5.3.1, radiated Tx power of mmW Band n261 and n260 for the beams tested is converted by applying the corresponding measured worst-case 4cm²PD values, and listed in below Table 12-3. Qualcomm Smart Transmit feature operates based on time-averaged Tx power reported on a per symbol basis, which is independent of modulation, channel and bandwidth (RBs), therefore the worst-case 4cm²PD was conducted with the EUT in FTM mode, with CW modulation and 100% duty cycle. cDASY6 system verification for power density measurement is provided in Section 14, and the associated SPEAG certificates are attached in Appendix G.

Both the worst-case 1gSAR and 4cm²PD values used in this section are listed in Table 12-3. The measured EIRP at *input.power.limit* for the beams tested in this section are also listed in Table 12-3.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 62 of 86
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 63 of 86
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04/06/2020

					Measured input.pov	-	
Tech	Band	Antenna	Beam ID	input.power.limit (dBm)	4cm ² psPD (W/m ²)	Test Position	Measured EIRP at input.power.limit (dBm)
mmW NR	n261	0	24	4	5.87	Back	11.35
		0	0	9.5	6.18	Back	8.63
mmW NR	mW NR n260		24	5.6	6.81	Back	8.45
	11260	0	0	10.4 -> 8.5	5.5	Back	4.05

Table 12-3 Worst-case 1gSAR, 4cm² avg. PD and EIRP measured at *input.power.limit* for the selected configurations

Tech	Band	Antenna	DSI	Measured Plimit (dBm)	Measured 1g SAR at Plim	
Teen		Antenna			1g SAR (W/kg)	Test Position
LTE	2	1	3	12.91	0.671	Top Edge

*The input.power.limit for n260 beam 0 is 10.4 dBm. However, the maximum input power of SDX55/QTM535 for n261 CP-OFDM modulation is 8.5dBm for the test configuration used, thus, the input.power.limit was adjusted to 8.5 dBm in the static PD measurement via FTM for n260 beam 0 to obtain the maximum PD exposure for CP-OFDM modulation.

The 4cm² psPD distributions for the highest PD value per band, as listed in Table 12-3, are plotted below.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		D
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 64 of 86
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Figure 12-1 4cm² psPD distribution measured at *input.power.limit* of 9.5 dBm on the back surface for n261 beam 0

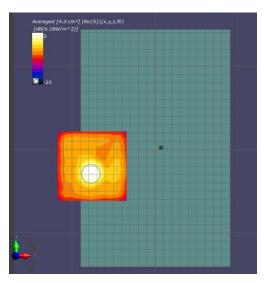
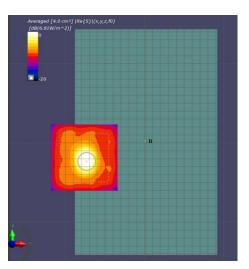


Figure 12-2 4cm² psPD distribution measured at *input.power.limit* of 5.6 dBm on the back surface for n260 beam 24



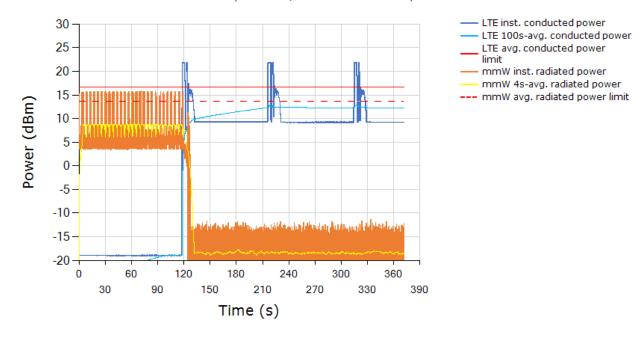
FCC ID: A3LSMT978U	Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		D	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 65 of 86	
2020 PCTEST				REV 1. 04/06/202	

13 RADIATED POWER TX CASES (FREQ > 6 GHZ)

13.1 Maximum Tx power test results for n261

This test was measured with LTE 2 and mmW Band n261 Beam ID 24, by following the detailed test procedure described in Section 5.3.1.

Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:



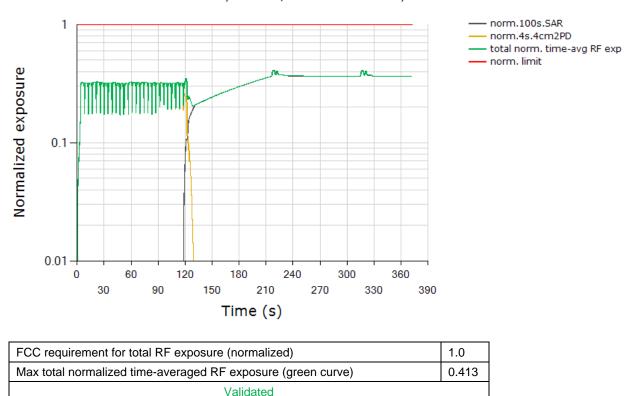
LTE and mmW Instantaneous and Time-averaged TX Power Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

Above time-averaged conducted Tx power for LTE 2 and radiated Tx power for mmW NR n261 beam 24 are converted into time-averaged 1gSAR and time-averaged 4cm²PD using Equation (2a) and (2b), which are divided by FCC 1gSAR limit of 1.6 W/kg and 4cm²PD limit of 10 W/m². respectively, to obtain normalized exposures versus time. Below plot shows (a) normalized time-averaged 1gSAR versus time, (b) normalized time-averaged 4cm2-avg.PD versus time, (c) sum of normalized time-averaged 1gSAR and normalized time-averaged 4cm²-avg.PD:

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Document S/N:	Test Dates:	DUT Type:		Daga 66 of 86
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 66 of 86
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04/06/2020



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

<u>Plot notes:</u> As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 24 of (75% * 5.87 W/m²)/(10 W/m²) = 44.0% \pm 2.1dB device related uncertainty (see green/orange curve between 0s~120s). At ~120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of (100% * 0.671 W/kg)/(1.6 W/kg) = 41.9% \pm 1dB design related uncertainty (see black curve approaching this level towards end of the test).

As can be seen, the power limiting enforcement is effective and the total normalized timeaveraged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

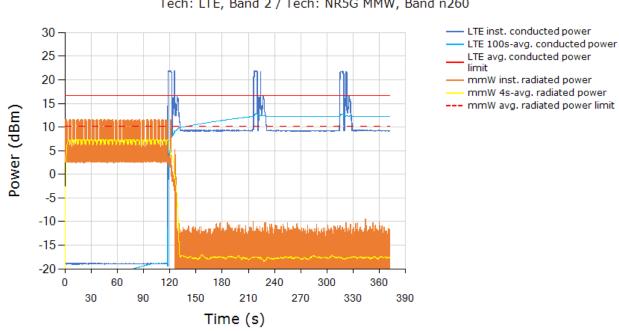
FCC ID: A3LSMT978U	PCTEST [*] Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dana 07 of 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 67 of 86
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REV 1.0 04/06/2020

13.2 Maximum Tx power test results for n260

This test was measured with LTE 2 and mmW Band n260 Beam ID 24, by following the detailed test procedure described in Section 5.3.1.

Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:

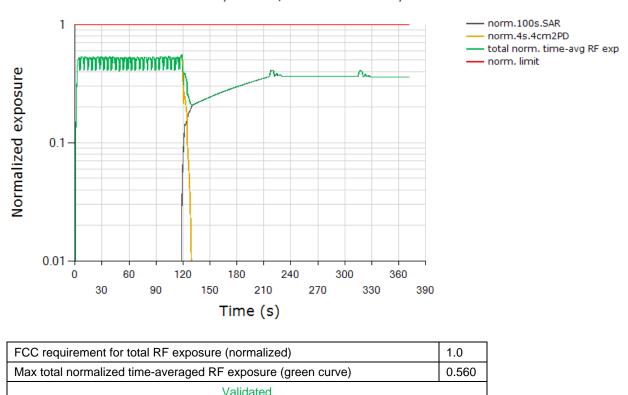


LTE and mmW Instantaneous and Time-averaged TX Power Tech: LTE, Band 2 / Tech: NR5G MMW, Band n260

Above time-averaged conducted Tx power for LTE 2 and radiated Tx power for mmW NR n260 beam 24 are converted into time-averaged 1gSAR and time-averaged 4cm²PD using Equation (2a) and (2b), which are divided by FCC 1gSAR limit of 1.6 W/kg and 4cm²PD limit of 10 W/m², respectively, to obtain normalized exposures versus time. Below plot shows (a) normalized time-averaged 1gSAR versus time, (b) normalized time-averaged 4cm2-avg.PD versus time, (c) sum of normalized time-averaged 1gSAR and normalized time-averaged 4cm²-avg.PD:

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 68 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
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04/06/2020



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n260

<u>Plot notes:</u> As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 24 of (75% * 6.81 W/m²)/(10 W/m²) = 51.1% \pm 2.1dB device related uncertainty (see green/orange curve between 0s~120s). At ~120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of (100% * 0.671 W/kg)/(1.6 W/kg) = 41.9% \pm 1dB design related uncertainty (see black curve approaching this level towards end of the test).

As can be seen, the power limiting enforcement is effective and the total normalized timeaveraged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

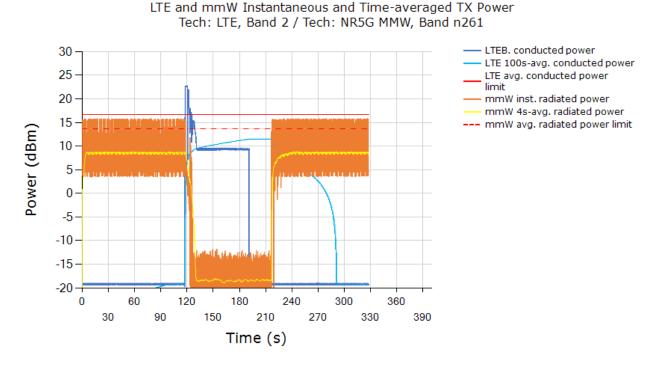
FCC ID: A3LSMT978U	PCTEST [®] Proud to be part of [®] element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 69 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
© 2020 PCTEST				REV 1.0	

REV 1.0 04/06/2020

13.3 Switch in SAR vs. PD exposure test results for n261

This test was measured with LTE Band 2 (DSI = 3) and mmW Band n261 Beam ID 24, by following the detailed test procedure is described in Section 5.3.2.

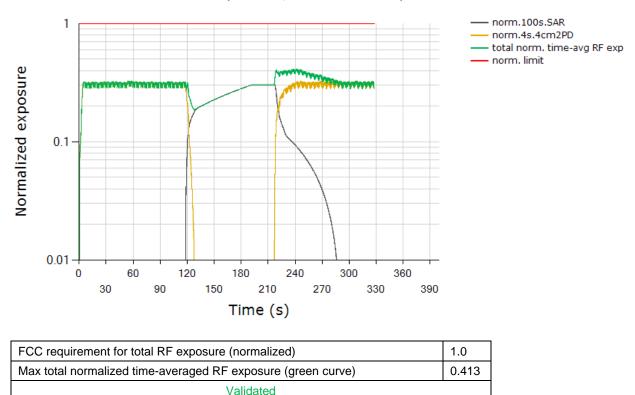
Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:



From the above plot, it is predominantly instantaneous PD exposure between $0s \sim 120s$, it is instantaneous SAR+PD exposure between 120s ~ 140s, it is predominantly instantaneous SAR exposure between 140s ~ 200s, and above 200s, it is predominantly instantaneous PD exposure.

Normalized time-averaged exposures for LTE (1gSAR) and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:

FCC ID: A3LSMT978U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Dama 70 of 00	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 70 of 86	
© 2020 PCTEST				REV 1.0 04/06/2020	



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

Plot notes: As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 24 of $(75\% * 5.87 \text{ W/m}^2)/(10 \text{ W/m}^2) = 44.0\% \pm 2.1 \text{dB}$ device related uncertainty (see orange/green curve between 0s~120s). At ~120s time mark. LTE is set to all-up bits, taking away margin from mmW exposure gradually (orange curve for mmW exposure goes down while black curve for LTE exposure goes up). At ~200s time mark, LTE is set to all-down bits, which results in mmW getting back RF margin slowly as seen by gradual increase in mmW exposure (orange curve for mmW exposure goes up while black curve for LTE exposure goes down). The calculated maximum RF exposure from LTE corresponds to normalized 1gSAR exposure value of (100% * 0.671 W/kg)/(1.6 W/kg) = 41.9% ± 1dB design related uncertainty (note that this level will be achieved by green and black curves if LTE remains in all-up bits for longer time duration which was already demonstrated in maximum Tx power test in Section 13.1). Total normalized time-averaged exposure (green curve) for this test should be within the calculated range between $44.0\% \pm 2.1$ dB device related uncertainty (only PD exposure) and $41.9\% \pm 1$ dB design related uncertainty (only SAR exposure).

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Document S/N:	Test Dates:	DUT Type:		Page 71 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
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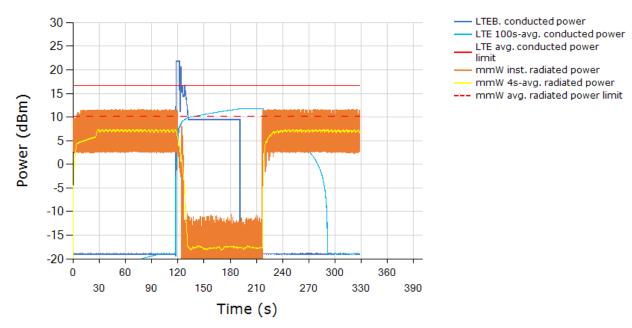
04/06/2020

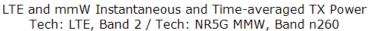
As can be seen, the power limiting enforcement is effective during transmission when SAR and PD exposures are switched, and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

13.4 Switch in SAR vs. PD exposure test results for n260

This test was measured with LTE Band 2 (DSI =3) and mmW Band n260 Beam ID 24, by following the detailed test procedure is described in Section 5.3.2.

Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:



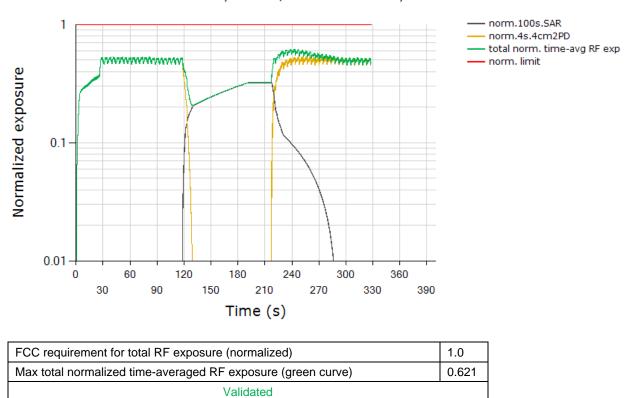


From the above plot, it is predominantly instantaneous PD exposure between 0s ~ 120s, it is instantaneous SAR+PD exposure between 120s ~ 140s, it is predominantly instantaneous SAR exposure between 140s ~ 200s, and above 200s, it is predominantly instantaneous PD exposure

Normalized time-averaged exposures for LTE (1gSAR) and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:

FCC ID: A3LSMT978U	Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 72 of 86	
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet			
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REV 1.0 04/06/2020



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n260

Plot notes: As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 24 of (75% * 6.81 W/m²)/(10 W/m²) = 51.1% ± 2.1dB device related uncertainty (see orange/green curve between 0s~120s). At ~120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually (orange curve for mmW exposure goes down while black curve for LTE exposure goes up). At ~200s time mark, LTE is set to all-down bits, which results in mmW getting back RF margin slowly as seen by gradual increase in mmW exposure (orange curve for mmW exposure goes up while black curve for LTE exposure goes down). The calculated maximum RF exposure from LTE corresponds to normalized 1gSAR exposure value of (100% * 0.671 W/kg)/(1.6 W/kg) = 41.9% ± 1dB design related uncertainty (note that this level will be achieved by green and black curves if LTE remains in all-up bits for longer time duration which was already demonstrated in maximum Tx power test in Section 13.1). Total normalized time-averaged exposure (green curve) for this test should be within the calculated range between 51.1% ± 2.1dB device related uncertainty (only PD exposure) and 41.9% ± 1dB design related uncertainty (only SAR exposure).

FCC ID: A3LSMT978U	PCTEST [®] Proud to be part of [®] element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 72 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 73 of 86
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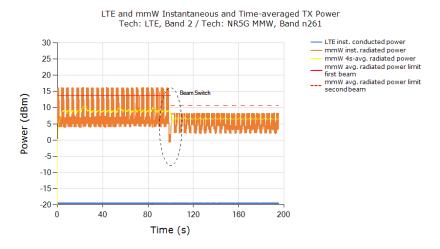
04/06/2020

As can be seen, the power limiting enforcement is effective during transmission when SAR and PD exposures are switched, and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

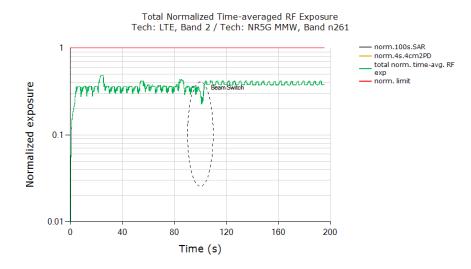
13.5 Change in Beam test results for n261

This test was measured with LTE Band 2 (DSI = 3) and mmW Band n261, with beam switch from Beam ID 24 to Beam ID 0, by following the test procedure is described in Section 5.3.3.

Instantaneous conducted LTE Tx power versus time, instantaneous and 4s-averaged radiated mmW Tx power versus time, time-averaged radiated mmW Tx power limits for beam 24 and beam 0:



Normalized time-averaged exposures for LTE and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:



FCC requirement for total RF exposure (normalized)	1.0
Max total normalized time-averaged RF exposure (green curve)	
Validated	

FCC ID: A3LSMT978U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dara 74 at 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 74 of 86
© 2020 PCTEST				REV 1.0

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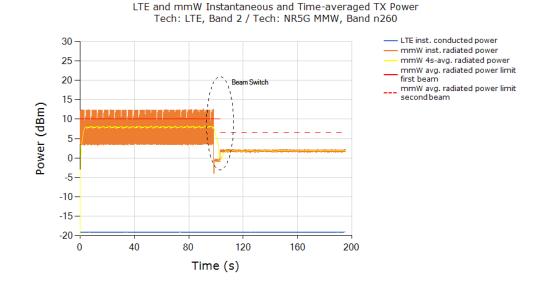
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<u>Plot notes:</u> 5G mmW NR call was established at ~1s time mark and LTE was placed in all-down bits immediately after 5G mmW NR call was established. For the rest of this test, mmW exposure is the dominant contributor as LTE is left in all-down bits. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, exposure between 1s ~100s corresponds to a normalized 4cm²PD exposure value for Beam ID 24 of (75% * 5.87 W/m²)/(10 W/m²) = 44.0% ± 2.1dB device related uncertainty. At ~100s time mark (shown in black dotted ellipse), beam was switched to Beam ID 0. Note that the *input.power.limit* for Beam ID 0 is 9.5dBm, however the maximum input power for n261 CP-OFDM modulation is capped at 9.5 dBm.). From Table 12-3, exposure between 100s ~200s corresponds to a normalized 4cm²PD exposure value for Beam ID 0 of (75% * 6.18 W/m²)/(10 W/m²) = 46.4% ± 2.1dB device related uncertainty. Additionally, during the switch, the ratio between the averaged radiated powers of the two beams (yellow curve) should correspond to the difference in EIRPs measured at each corresponding *input.power.limit* for these beams listed in Table 12-3, i.e., 2.72 dB ± 2.1dB device uncertainty.

13.6 Change in Beam test results for n260

This test was measured with LTE Band 2 (DSI = 3) and mmW Band n260, with beam switch from Beam ID 24 to Beam ID 0, by following the test procedure is described in Section 5.3.3.

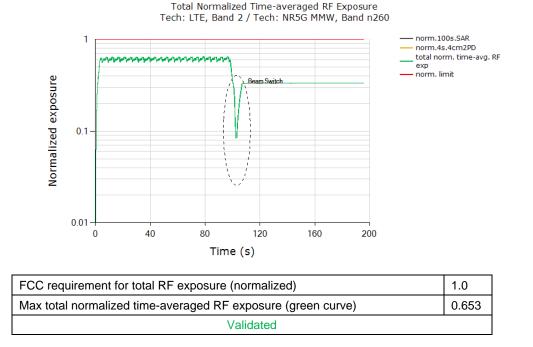
Instantaneous conducted LTE Tx power versus time, instantaneous and 4s-averaged radiated mmW Tx power versus time, time-averaged radiated mmW Tx power limits for beam 24 and beam 0:



Normalized time-averaged exposures for LTE and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 75 of 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 75 of 86
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Plot notes: 5G mmW NR call was established at ~1s time mark and LTE was placed in all-down bits immediately after 5G mmW NR call was established. For the rest of this test, mmW exposure is the dominant contributor as LTE is left in all-down bits. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, exposure between 1s ~100s corresponds to a normalized 4cm²PD exposure value for Beam ID 24 of (75% * 6.81 W/m²)/(10 W/m^2) = 51.1% ± 2.1dB device related uncertainty. At ~100s time mark (shown in black dotted ellipse), beam was switched to Beam ID 0. Note that the input.power.limit for Beam ID 0 is 10.4 dBm, however the maximum input power for n260 CP-OFDM modulation is capped at 8.5dBm, therefore, there is no power limiting required when in n260 Beam ID 0, resulting in flat line in power plot for instantaneous radiated power after switch. Note that at 8.5dBm max power, it is 1.9dB (64.6% in linear units) lower than input.power.limit. Since the callbox is configured to transmit at 75.6% duty cycle, the maximum average power consumes 64.6% x 75.6% = 48.8% of RF exposure margin utilized by Beam ID 0 (less than 75% allocated margin for mmW by Smart Transmit). Therefore, Smart Transmit allows Beam ID 0 to transmit at maximum power continuously at 75.6% duty cycle. Therefore, the normalized 4cm²PD exposure value for n260 Beam ID 0 = (100% * 75.6% callbox duty cycle * 5.5W/m²)/(10 W/m²) = 41.6% ± 2.1dB device related uncertainty. Additionally, during the switch, the ratio between the averaged radiated powers of the two beams (yellow curve) should correspond to the difference in EIRPs measured at each corresponding *input.power.limit* for these beams listed in Table 12-3, i.e., 4.4dB ± 2.1dB device uncertainty.

FCC ID: A3LSMT978U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 76 of 86
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04/06/2020

14 SYSTEM VERIFICATION (FREQ > 6 GHZ)

The system was verified to be within ±0.66 dB of the power density targets on the calibration certificate according to the test system specification in the user's manual and calibration facility recommendation. The 0.66 dB deviation threshold represents the expanded uncertainty for system performance checks using SPEAG's mmWave verification sources. The same spatial resolution and measurement region used in the source calibration was applied during the system check.

The measured power density distribution of verification source was also confirmed through visual inspection to have no noticeable differences, both spatially (shape) and numerically (level) from the distribution provided by the manufacturer, per November 2017 TCBC Workshop Notes.

	System Verification									
Syst.	Freq. (GHz)	Date	Source SN	Probe SN	Normal psPD (W/m	² over 4 cm ²)	Deviation (dB)	Total psPD (W/m ² over 4 cm ²)		Deviation (dB)
			SIN		measured	target		measured	target	
Ν	30	08/3/2020	1043	9364	25.10	26.40	-0.22	25.50	26.70	-0.20
Ν	30	08/4/2020	1043	9364	25.20	26.40	-0.20	25.50	26.70	-0.20

Table 14-1 System Verification Results

Note: A **10 mm distance spacing** was used from the reference horn antenna aperture to the probe element. This includes 4.45 mm from the reference antenna horn aperture to the surface of the verification source plus 5.55 mm from the surface to the probe. The SPEAG software requires a setting of "5.55 mm" for the correct set up.

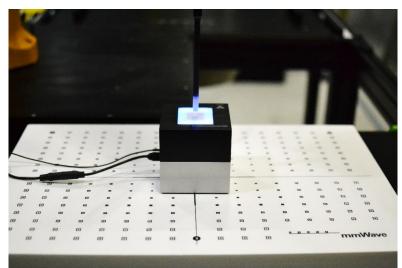


Figure 14-1 System Verification Setup Photo

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 77 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 77 of 86
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15 POWER DENSITY TEST RESULTS (FREQ > 6 GHZ)

15.1 PD measurement results for maximum power transmission scenario

The following configurations were measured by following the detailed test procedure is described in Section 5.4:

- 1. LTE Band 2 (DSI =3) and mmW Band n261 Beam ID 24
- 2. LTE Band 2 (DSI =3) and mmW Band n260 Beam ID 24

The measured conducted Tx power of LTE and ratio of $\frac{[pointE(t)]^2}{[pointE_input.power.limit]^2}$ of mmW is converted into 1gSAR and 4cm²PD value, respectively, using Eq. (4a) and (4b), rewritten below:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(4a)

 $4cm^2 PD(t) = \frac{[pointE(t)]^2}{[pointE_input.power.limit]^2} * 4cm^2 PD_input.power.limit$ (4b)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC SAR limit} + \frac{\frac{1}{T_{PD}}\int_{t-T_{PD}}^{t} 4cm^{2}PD(t)dt}{FCC 4cm^{2}PD limit} \le 1$$
(4c)

where, $conducted_Tx_power(t)$, $conducted_Tx_power_P_{limit}$, and $1g_or_10gSAR_P_{limit}$ correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at P_{limit} , and measured 1gSAR or 10gSAR values at P_{limit} corresponding to LTE transmission. Similarly, pointE(t), $pointE_input.power.limit$, and $4cm^2PD@input.power.limit$ correspond to the measured instantaneous E-field at *input.power.limit*, and $4cm^2PD$ value at *input.power.limit*. corresponding to mmW transmission.

NOTE: cDASY6 system measures relative E-field, and provides ratio of $\frac{[pointE(t)]^2}{[pointE_input.power.limit]^2}$ versus time.

The radio configurations tested are described in Table 12-1 and Table 12-2. The 1gSAR at P_{limit} for LTE 2 DSI = 3, the measured 4cm²PD at *input.power.limit* of mmW n261 beam 24 and n260 beam 24, are all listed in Table 12-3.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 70 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 78 of 86
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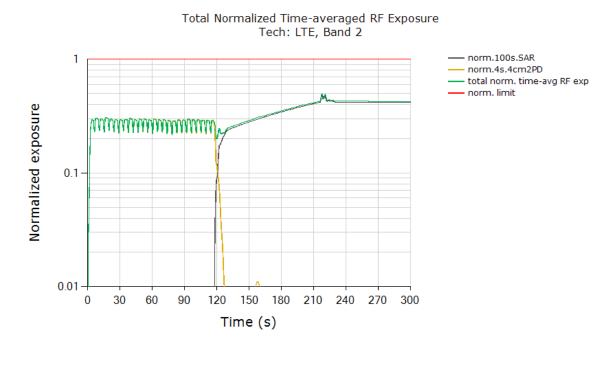
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04/06/2020

15.1.1 PD test results for n261

Step 2.e plot (in Section 5.4) for normalized instantaneous and time-averaged exposures for LTE and mmW n261 beam 24



FCC limit for total RF exposure (normalized)	1.0
Max total normalized time-averaged RF exposure (green curve)	0.505
Validated	

<u>Plot notes</u>: LTE was placed in all-down bits immediately after 5G mmW NR call was established. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized $4cm^2PD$ exposure value for Beam ID 24 of $(75\% * 5.87 \text{ W/m}^2)/(10 \text{ W/m}^2) = 44.0\% \pm 2.1dB$ device related uncertainty (see orange/green curve between 0s~120s). Around 120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of the test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of $(100\% * 0.671 \text{ W/kg})/(1.6 \text{ W/kg}) = 41.9\% \pm 1dB$ design related uncertainty (see black curves approaching this level towards end of the test).

As can be seen, the power limiting enforcement is effective and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 70 of 00
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 79 of 86
© 2020 PCTEST				REV 1.0

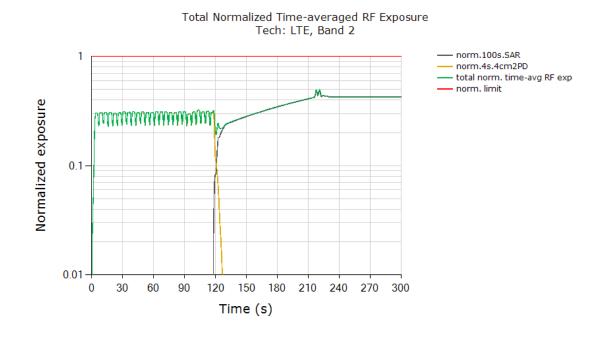
REV 1.0 04/06/2020

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15.1.2 PD test results for n260

Step 2.e plot (in Section 5.4) for normalized instantaneous and time-averaged exposures for LTE and mmW n260 beam 24



FCC limit for total RF exposure	1.0
Max total normalized time-averaged RF exposure (green curve)	0.503
Validated	

<u>Plot notes</u>: LTE was placed in all-down bits immediately after 5G mmW NR call was established. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized $4cm^2PD$ exposure value for Beam ID 24 of $(75\% * 6.81 \text{ W/m}^2)/(10 \text{ W/m}^2) = 51.1\% \pm 2.1dB$ device related uncertainty (see orange/green curve between 0s~120s). Around 120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of the test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of $(100\% * 0.671 \text{ W/kg})/(1.6 \text{ W/kg}) = 41.9\% \pm 1dB$ design related uncertainty (see black curves approaching this level towards end of the test).

As can be seen, the power limiting enforcement is effective and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 80 of 86
© 2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

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16 EQUIPMENT LIST

Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
8594A	(9kHz-2.9GHz) Spectrum Analyzer	N/A	N/A	N/A	3051A00187
E4438C	ESG Vector Signal Generator	3/8/2019	Biennial	3/8/2021	MY42082385
N9020A	MXA Signal Analyzer	12/19/2019	Annual	12/19/2020	MY48010233
N5182A	MXG Vector Signal Generator	8/19/2019	Annual	8/19/2020	MY47420837
8753ES	S-Parameter Network Analyzer	12/31/2019	Annual	12/31/2020	US39170122
N5182A	MXG Vector Signal Generator	5/13/2020	Annual	5/13/2021	MY47420603
E4438C	ESG Vector Signal Generator	3/8/2019	Biennial	3/8/2021	MY42082385
E4438C	ESG Vector Signal Generator	3/11/2019	Biennial	3/11/2021	MY45090700
8753ES	S-Parameter Network Analyzer	1/16/2020	Annual	1/16/2021	US39170118
8753ES	S-Parameter Network Analyzer	8/26/2019	Annual	8/26/2020	MY40000670
8753ES	S-Parameter Vector Network Analyzer	9/19/2019	Annual	9/19/2020	MY40003841
15S1G6	Amplifier	CBT	N/A	CBT	433972
15S1G6	Amplifier	CBT	N/A	CBT	433974
ML2495A	Power Meter	12/17/2019	Annual	12/17/2020	941001
MA24106A	USB Power Sensor	2/27/2020	Annual	2/27/2021	1520501
MA24106A	USB Power Sensor	2/27/2020	Annual	2/27/2021	1520503
ML2496A	Power Meter	12/17/2019	Annual	12/17/2020	1138001
MA2411B	Pulse Power Sensor	12/4/2019	Annual	12/4/2020	0846215
MA2411B	Pulse Power Sensor	12/4/2019	Annual	12/4/2020	1126066
AR85729-5/5759B	Solid State Amplifier	CBT	N/A	CBT	M3W1A00-1002
AR85729-5	Solid State Amplifier	CBT	N/A	CBT	M1S5A00-009
4040	Therm./ Clock/ Humidity Monitor	10/9/2018	Biennial	10/9/2020	181647811
4352	Long Stem Thermometer	6/26/2019	Biennial	6/26/2021	192282753
4352	Ultra Long Stem Thermometer	11/29/2018	Biennial	11/29/2020	181766817
11SH10-1300/U4000	High Pass Filter	N/A	N/A	N/A	11SH10-1300/U4000
772D	Dual Directional Coupler	CBT	N/A	CBT	MY52180215
E7515B	UXM 5G Wireless Test Platform	6/11/2019	Annual	12/11/2020	MY59150289
M1740A	mmWave Transceiver	5/7/2019	Annual	11/7/2020	MY58481076
M1740A	mmWave Transceiver	5/7/2019	Annual	11/7/2020	MY58481133
E7770A	Common Interface Unit	4/29/2019	Annual	10/29/2020	MY58290483
110067006	Directional Coupler, 10 - 67 GHz	N/A	N/A	N/A	200391
BW-N6W5+	6dB Attenuator	CBT	N/A	CBT	1139
ZA2PD2-63-S+	Power Splitter	CBT	N/A	CBT	SUU64901930
ZAPD-2-272-S+	Power Splitter	CBT	N/A	CBT	SF702001405
NLP-1200+	Low Pass Filter	N/A	N/A	N/A	VUU78201318
SLP-2400+	Low Pass Filter	CBT	N/A	CBT	R8979500903
VLF-6000+	Low Pass Filter	CBT	N/A	CBT	N/A
BW-N20W5+	DC to 18 GHz Precision Fixed 20 dB Attenuator	CBT	N/A	CBT	N/A
NLP-2950+	Low Pass Filter DC to 2700 MHz	CBT	N/A	CBT	N/A
NLP-1200+	Low Pass Filter DC to 1000 MHz	CBT	N/A	CBT	N/A
BW-N20W5	Power Attenuator	CBT	N/A	CBT	1226
4216-10	Directional Coupler, 0.5 to 8.0 GHz, 10 dB	5/16/2019	Annual	11/16/2020	01492
4216-10	Directional Coupler, 0.5 to 8.0 GHz, 10 dB	5/16/2019	Annual	11/16/2020	01493
4772-3	Attenuator	CBT	N/A	CBT	9406
BW-S3W2	Attenuator	CBT	N/A	CBT	120
BW-S10W2+	Attenuator	CBT	N/A	CBT	831
4014C-6	4 - 8 GHz SMA 6 dB Directional Coupler	CBT	N/A	CBT	N/A
NSC-G2	Motion Controller	CBT	N/A	CBT	1007-D
PE2208-6	Bidirectional Coupler	CBT	N/A	CBT	N/A
PE2209-10	Bidirectional Coupler	CBT	N/A	CBT	N/A
STE6300	Shielded Test Enclosure	N/A	N/A	N/A	1310
CMW500	Radio Communication Tester	8/26/2019	Annual	8/26/2020	100976
NRP8S	3-Path Dipole Power Sensor	6/1/2019	Annual	12/1/2020	108168
NRP8S	3-Path Dipole Power Sensor	6/1/2019	Annual	12/1/2020	108523
NRP8S	3-Path Dipole Power Sensor	6/10/2020	Annual	6/10/2021	109322
NRP50S	3-Path Dipole Power Sensor	6/1/2019	Annual	12/1/2020	101164
Verification Source 30GHz	30GHz System Verification Antenna	2/12/2020	Annual	6/19/2021	1043
EUmmWV3	E-field Probe	6/24/2020	Annual	6/24/2021	9364
DAE4	Dasy Data Acquisition Electronics	4/15/2020	Annual	4/15/2021	1582
DAE4	Dasy Data Acquisition Electronics	12/18/2019	Annual	12/18/2020	859
DAK-3.5	Dielectric Assessment Kit	10/22/2019	Annual	10/22/2020	1091
D835V2	835 MHz SAR Dipole	1/13/2020	Annual	1/13/2021	4d132
D1750V2	1750 MHz SAR Dipole	10/22/2018	Biennial	10/22/2020	1150
D1900V2	1900 MHz SAR Dipole	2/21/2019	Biennial	2/21/2021	5d148
D2600V2	2600 MHz SAR Dipole	4/11/2018	Triennial	4/11/2021	1004
EX3DV4	SAR Probe	3/18/2020	Annual	3/18/2021	7526

Notes:

- 1. CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, amplifier, attenuator, coupler, or filter were connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements. Each equipment item is used solely within its respective calibration period. 2.
- Due to the worldwide pandemic caused by the novel SAR-CoV-2 virus (COVID-19), special calibration extensions have been permitted 3. by A2LA. Some equipment had its calibration period extended accordingly and will be calibrated when possible.

FCC ID: A3LSMT978U	PCTEST [°] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 84 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 81 of 86
© 2020 PCTEST				REV 1.0

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17 **MEASUREMENT UNCERTAINTIES**

For SAR Measurements

Measurements								
a	С	d	e=	f	g	h =	i =	k
			f(d,k)			c x f/e	c x g/e	
	Tol.	Prob.		ci	c _i	1gm	10gms	
Uncertainty Component	(± %)	Dist.	Div.	1gm	10 gms	ui	ui	vi
				-	_	(± %)	(± %)	
Measurement System								
Probe Calibration	6.55	Ν	1	1.0	1.0	6.6	6.6	x
Axial Isotropy	0.25	Ν	1	0.7	0.7	0.2	0.2	8
Hemishperical Isotropy	1.3	Ν	1	0.7	0.7	0.9	0.9	8
Boundary Effect	2.0	R	1.73	1.0	1.0	1.2	1.2	8
Linearity	0.3	Ν	1	1.0	1.0	0.3	0.3	x
System Detection Limits	0.25	R	1.73	1.0	1.0	0.1	0.1	x
Readout Electronics	0.3	Ν	1	1.0	1.0	0.3	0.3	x
Response Time	0.8	R	1.73	1.0	1.0	0.5	0.5	x
Integration Time	2.6	R	1.73	1.0	1.0	1.5	1.5	x
RF Ambient Conditions - Noise	3.0	R	1.73	1.0	1.0	1.7	1.7	x
RF Ambient Conditions - Reflections	3.0	R	1.73	1.0	1.0	1.7	1.7	x
Probe Positioner Mechanical Tolerance	0.4	R	1.73	1.0	1.0	0.2	0.2	x
Probe Positioning w/ respect to Phantom	6.7	R	1.73	1.0	1.0	3.9	3.9	x
Extrapolation, Interpolation & Integration algorithms for Max. SAR Evaluation	4.0	R	1.73	1.0	1.0	2.3	2.3	x
Test Sample Related								
Test Sample Positioning	2.7	Ν	1	1.0	1.0	2.7	2.7	35
Device Holder Uncertainty	1.67	Ν	1	1.0	1.0	1.7	1.7	5
Output Power Variation - SAR drift measurement	5.0	R	1.73	1.0	1.0	2.9	2.9	00
SAR Scaling	0.0	R	1.73	1.0	1.0	0.0	0.0	x
Phantom & Tissue Parameters								
Phantom Uncertainty (Shape & Thickness tolerances)	7.6	R	1.73	1.0	1.0	4.4	4.4	x
Liquid Conductivity - measurement uncertainty	4.2	N	1	0.78	0.71	3.3	3.0	10
Liquid Permittivity - measurement uncertainty	4.1	Ν	1	0.23	0.26	1.0	1.1	10
Liquid Conductivity - Temperature Uncertainty	3.4	R	1.73	0.78	0.71	1.5	1.4	x
Liquid Permittivity - Temperature Unceritainty	0.6	R	1.73	0.23	0.26	0.1	0.1	x
Liquid Conductivity - deviation from target values	5.0	R	1.73	0.64	0.43	1.8	1.2	x
Liquid Permittivity - deviation from target values	5.0	R	1.73	0.60	0.49	1.7	1.4	x
Combined Standard Uncertainty (k=1)		RSS				11.5	11.3	60
Expanded Uncertainty		k=2				23.0	22.6	
(95% CONFIDENCE LEVEL)								

	FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 92 of 96
	1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 82 of 86
C	2020 PCTEST				REV 1.0

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For PD Measurements

					f =	
а	b	С	d	e	b x e/d	g
	Unc.	Prob.			ui	
Uncertainty Component	(± dB)	Dist.	Div.	ci	(± dB)	vi
Calibration	0.49	Ν	1	1.0	0.49	∞
Probe correction	0	R	1.73	1.0	0.00	~
Frequency Response (BW ≤ 1 GHz)	0.20	R	1.73	1.0	0.12	~
Sensor cross coupling	0	R	1.73	1.0	0.00	∞
Isotropy	0.50	R	1.73	1.0	0.29	∞
Linearity	0.20	R	1.73	1.0	0.12	~
Probe Scattering	0	R	1.73	1.0	0	∞
Probe Positioning Offset	0.30	R	1.73	1.0	0.17	~
Probe Positioning Repeatability	0.04	R	1.73	1.0	0.02	∞
Sensor Mechanical Offset	0	R	1.73	1.0	0	~
Probe Spatial Resolution	0	R	1.73	1.0	0	∞
Field Impedance Dependence	0	R	1.73	1.0	0	∞
Amplitude and phase drift	0	R	1.73	1.0	0	~
Amplitude and phase noise	0.04	R	1.73	1.0	0.02	∞
Measurement area truncation	0	R	1.73	1.0	0	∞
Data acquisition	0.03	Ν	1	1.0	0.03	~
Sampling	0	R	1.73	1.0	0	~
Field Reconstruction	0.60	R	1.73	1.0	0.35	~
Forward Transformation	0	R	1.73	1.0	0	~
Power Density Scaling	-	R	1.73	1.0	-	~
Spatial Averaging	0.10	R	1.73	1.0	0.06	~
System Detection Limit	0.04	R	1.73	1.0	0.02	~
Test Sample and Environmental Factors					•	
Probe Coupling with DUT	0	R	1.73	1.0	0	~
Modulation Response	0.40	R	1.73	1.0	0.23	~
Integration Time	0	R	1.73	1.0	0	~
Response Time	0	R	1.73	1.0	0	8
Device Holder Influence	0.10	R	1.73	1.0	0.06	~
DUT Alignment	0	R	1.73	1.0	0	∞
RF Ambient Conditions	0.04	R	1.73	1.0	0.02	∞
Ambient Reflections	0.04	R	1.73	1.0	0.02	~
Immunity / Secondary Reception	0	R	1.73	1.0	0	~
Drift of the DUT	0.22	R	1.73	1.0	0.13	~~
Combined Standard Uncertainty (k=1)		RSS			0.76	∞
(95% CONFIDENCE LEVEL)	k=2		1.53			

FCC ID: A3LSMT978U	Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 82 of 96
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 83 of 86
© 2020 PCTEST				REV 1 (

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18 CONCLUSION

18.1 Measurement Conclusion

The SAR evaluation indicates that the DUT complies with the RF radiation exposure limits of the FCC and Innovation, Science, and Economic Development Canada, with respect to all parameters subject to this test. These measurements were taken to simulate the RF effects of RF exposure under worst-case conditions. Precise laboratory measures were taken to assure repeatability of the tests. The results and statements relate only to the item(s) tested.

Please note that the absorption and distribution of electromagnetic energy in the body are very complex phenomena that depend on the mass, shape, and size of the body, the orientation of the body with respect to the field vectors, and the electrical properties of both the body and the environment. Other variables that may play a substantial role in possible biological effects are those that characterize the environment (e.g. ambient temperature, air velocity, relative humidity, and body insulation) and those that characterize the individual (e.g. age, gender, activity level, debilitation, or disease). Because various factors may interact with one another to vary the specific biological outcome of an exposure to electromagnetic fields, any protection guide should consider maximal amplification of biological effects as a result of field-body interactions, environmental conditions, and physiological variables. [3]

FCC ID: A3LSMT978U	PCTEST [*] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates: DUT Type: -R1.A3L 07/21/2020 - 08/05/2020 Portable Tablet			
1M2004230075-25-R1.A3L				Page 84 of 86
© 2020 PCTEST	·	·		REV 1.0

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04/06/2020

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FCC ID: A3LSMT978U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 85 of 86
© 2020 PCTEST		·		REV 1.0

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04/06/2020

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- [24] SAR Measurement Guidance for IEEE 802.11 Transmitters, KDB Publication 248227 D01
- [25] FCC SAR Considerations for Handsets with Multiple Transmitters and Antennas, KDB Publications 648474 D03-D04
- [26] FCC SAR Evaluation Considerations for Laptop, Notebook, Netbook and Tablet Computers, FCC KDB Publication 616217 D04
- [27] FCC SAR Measurement and Reporting Requirements for 100MHz 6 GHz, KDB Publications 865664 D01-D02
- [28] FCC General RF Exposure Guidance and SAR Procedures for Dongles, KDB Publication 447498, D01-D02
- [29] Anexo à Resolução No. 533, de 10 de Septembro de 2009.
- [30] IEC 62209-2, Human exposure to radio frequency fields from hand-held and body-mounted wireless communication devices - Human models, instrumentation, and procedures - Part 2: Procedure to determine the specific absorption rate (SAR) for wireless communication devices used in close proximity to the human body (frequency range of 30 MHz to 6 GHz), Mar. 2010.

FCC ID: A3LSMT978U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2004230075-25-R1.A3L	07/21/2020 - 08/05/2020	Portable Tablet		Page 86 of 86
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04/06/2020

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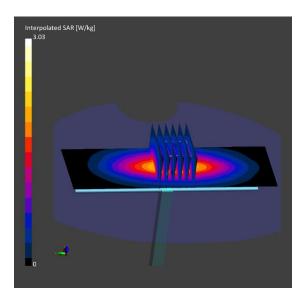
APPENDIX A: VERIFICATION PLOTS

Date: 07-21-2020 835MHz Body Verificaiton

Medium

Frequency [MHz]	TSL	TSL Conductivity [S/r	n] TSI	n] TSL Permittivity Ambier		t Temperature [C]	Tissue Temperature [C]
835.0	835 Body	0.99	54	.9	21 9		22.3
Exposure Co	nditions	5					
Phantom Section		Test Distance [mm]		Power [dBm]		Communication Syst	em, UID
Flat		15		23.0		CW, 0	
Hardware Se	tup						
Phantom		Dipole	Probe, Ca	libration Date		Conversion Factor	DAE, Calibration Date
Twin-SAM V8.0 (Rig	ht) – 1981	D835V2 - SN4d132	EX3DV4 -	SN7526, 2020-	03-18	9.55	DAE4 Sn859, 2019-12-18
Scans Setup		·					
				Ai	rea Scan		Zoom Scar
Grid Extents [mm]			60.0 × 90.0				50 0 x 30.0 x 30.0
Grid Steps [mm]			15.0 × 15.0				6.0 x 6.0 x 5.0
Sensor Surface [mm]			3.0)		
Graded Grid			No				
Grading Ratio					n/a		n/a

	Zoom Scan
psSAR1g [W/Kg]	2.01
psSAR10g [W/Kg]	1.32
Dev. 1g [%]	0.90



Date: 07-23-2020

835MHz Body Verification

Medium

Frequency [MHz]	TSL	TSL Conductivity	[S/m]	TSL Permittivity	Ambien	t Temperature [C]	Tissue Temperature [C]	
835.0	835 Body	0.98		55.1	22 0		22.0	
Exposure Co	nditions	5	· ·					
Phantom Section		Test Distance [mm]		Power [dBm]		Communication System, UID		
Flat		15		23.0		CW, 0		
Hardware Se	tup							
Phantom		Dipole	Probe,	Probe, Calibration Date		Conversion Factor DAE, Calibration Date		
Twin-SAM V8.0 (Rig	ght) – 1981	D835V2 - SN4d13	2 EX3DV	4 – SN7526, 2020	-03-18	9.55 DAE4 Sn859, 2019-		
Scans Setup								
					Area Scan		Zoom Scar	
Grid Extents [mm]				60.0 × 90.0		50 0 x 30.0 x 30		
Grid Steps [mm]				15.0 × 15.0		6.0 × 6.0 × 5.		
Sensor Surface [mm	1]				3.0	1.		

Measurement Results

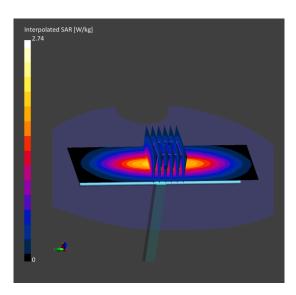
Graded Grid

Grading Ratio

	Zoom Scan
psSAR1g [W/Kg]	1.82
psSAR10g [W/Kg]	1.20
Dev. 1g [%]	-8.63

No

n/a



No

n/a

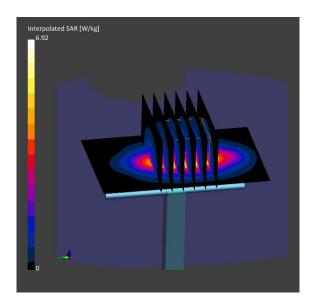
Date: 07-23-2020

1750MHz Body Verification

Medium

Frequency [MHz]	TSL	TSL Conductivity [S	/m] T	SL Permittivity	Ambier	nt Temperature [C]	Tissue Temperature [C]
1750.0	1750 Body	1.48	5	54.2			21.0
Exposure Co	nditions						
Phantom Section		Test Distance [mm]		Power [dBm]		Communication Syst	em, UID
Flat		10		20.0		CW, 0	
Hardware Se	tup						
Phantom		Dipole	Probe, Ca	libration Date		Conversion Factor	DAE, Calibration Date
Twin-SAM V8.0 (Rig	lht) – 1981	D1750V2 - SN1150	EX3DV4 -	- SN7526, 2020-	03-18	7.62	DAE4 Sn859, 2019-12-18
Scans Setup							
				A	rea Scan		Zoom Scan
Grid Extents [mm]		60.0 × 90.0		50 0 × 30.0 × 30.0			
Grid Steps [mm]			15.0 x 15.0		6.0 × 6.0 × 5.0		
Sensor Surface [mm]		3.0		1		
Graded Grid				No		No	
Grading Ratio			n/a		n/a		
Measuremen	t Result	5	1				
							Zoom Scan
psSAR1g [W/Kg]							3.91

psSAR1g [W/Kg]	3.91
psSAR10g [W/Kg]	2.10
Dev. 1g [%]	6.83

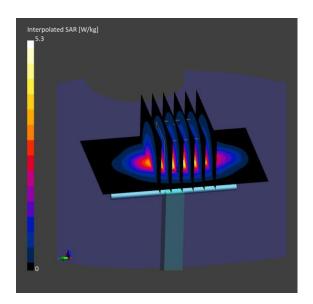


Date: 07-21-2020

1900MHz Body Verification

Medium

Frequency [MHz]	TSL	TSL C	Conductivity [S/r	n] T	SL Permittivity	Ambier	nt Temperature [C]	Tissue Temperature [C]	
1900.0	1900 Body 1.58		53.1 2		21.9		22.3		
Exposure Co	nditions	5							
Phantom Section		Test Dista	ance [mm]		Power [dBm]		Communication System, UID		
Flat		10			20.0		CW, 0		
Hardware Se	tup								
Phantom		Dipole		Probe, C	alibration Date		Conversion Factor	DAE, Calibration Date	
Twin-SAM V8.0 (Rig	D (Right) – 1981 D1900V2 – SN5d148		/2 – SN5d148	EX3DV4	- SN7526, 2020-(03-18	7.33	DAE4 Sn859, 2019–12–18	
Scans Setup									
					Are	ea Scan		Zoom Scan	
Grid Extents [mm]				60.0 × 90.0		50 0 x 30.0 x 30.0			
Grid Steps [mm]			15.0	x 15.0	15.0 6.0 x 6.				
Sensor Surface [mm]			3.0		1.4				
Graded Grid					No	No			
Grading Ratio			n/a		n/a				
Measuremen	t Result	S							
								Zoom Scan	
psSAR1g [W/Kg]						4.24			
psSAR10g [W/Kg]						2.20			
Dev. 1g [%]							8.44		

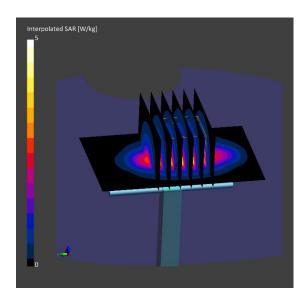


Date: 07-27-2020 1900MHz Body Verification

Medium

Frequency [MHz]	TSL	TSL Conductivity [S/	m] T	SL Permittivity	Ambier	nt Temperature [C]	Tissue Temperature [C]
1900.0	1900 Body 1.58		54	54.4 22.4			21.6
Exposure Co	nditions						
Phantom Section		Test Distance [mm]		Power [dBm]		Communication System	em, UID
Flat		10		20.0		CW, 0	
Hardware Set	tup			-			
Phantom	Dipole		Probe, Calibration Date		Conversion Factor	DAE, Calibration Date	
Twin-SAM V8.0 (Rig	ht) – 1981	D1900V2 - SN5d148	01900V2 - SN5d148 EX3DV4 -		4 - SN7526, 2020-03-18		DAE4 Sn859, 2019-12-18
Scans Setup		·					
				Ar	ea Scan		Zoom Scar
Grid Extents [mm]			60.0 × 90.0		x 90.0	50 0 x 30.0 x 30.	
Grid Steps [mm]			15.0 x 15.0		6.0 x 6.0 x 5		
Sensor Surface [mm]		3.0)			
Graded Grid			No		No	0 No	
Grading Ratio					n/a		n/a
Measuremen	t Result	S			L		

Zoom Scan psSAR1g [W/Kg] 4.01 psSAR10g [W/Kg] 2.07 Dev. 1g [%] 2.56



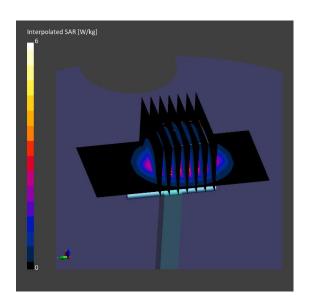
Date: 07-23-2020

2600MHz Body Verification

Medium

Dev. 1g [%]

Frequency [MHz]	TSL	TSL Conductivity [S	/m] T	SL Permittivity	Ambier	nt Temperature [C]	Tissue Temperature [C]	
2600.0	2450 Body 2.17		5	2.3	22.0		21.9	
Exposure Co	nditions	i			1			
Phantom Section		Test Distance [mm]		Power [dBm]		Communication Syst	em, UID	
Flat	Flat 10			20.0		CW, 0		
Hardware Se	tup							
Phantom		Dipole	Probe, Ca	alibration Date		Conversion Factor	DAE, Calibration Date	
Twin-SAM V8.0 (Rig	Jht) – 1981	D2600V2 - SN1004	EX3DV4 -	- SN7526, 2020-	03-18	7.0	DAE4 Sn859, 2019-12-18	
Scans Setup			1					
				Ai	ea Scan		Zoom Scan	
Grid Extents [mm]		48.0 x 96.0		50 0 x 30.0 x 30.0				
Grid Steps [mm]		12.0 x 12.0		5.0 x 5.0 x 5.0				
Sensor Surface [mm]					3.0	3.0		
Graded Grid					No	Ν		
Grading Ratio					n/a	n/a r		
Measuremen	t Result	s						
							Zoom Scan	
psSAR1g [W/Kg]						5.25		
psSAR10g [W/Kg]							2.34	



-4.20

Date: 08/03/2020

30 GHz System Verification

Device Under Test Properties

DUT	Serial Number
30 GHz Verification Source	1043

Exposure Conditions

Phantom Section	Position	Test Distance [mm]	Band	Frequency [MHz]
5G	FRONT	5.55	Validation band	30000 0

Hardware Setup

· · · · · · · · · · · · · · · · · · ·	
Probe, Calibration Date	DAE, Calibration Date
EUmmWV3 - SN9364, 06/24/2020	DAE4 SN1582, 04/15/2020

Software Setup

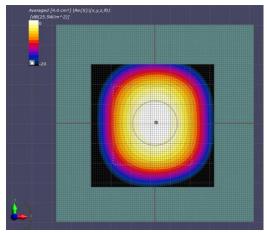
Software	Software Version
cDASY6 Module mmWave	2.0.2.34

Scans Setup

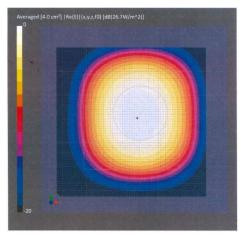
Scan Type	5G Scan
Grid Extents [mm]	60.0 × 60.0
Grid Steps [lambda]	0.25 x 0.25
Sensor Surface [mm]	5.55

Measurement Results

Scan Type	5G Scan
Avg. Area [cm²]	4.00
pS _{tot} avg [W/m ²]	25.5
pS _n avg [W/m ²]	25.1
E _{peak} [V/m]	115
Deviation (dB)	-0.20



30GHz System Verification



Calibration Certificate

Date: 08/04/2020

30 GHz System Verification

Device Under Test Properties

DUT	Serial Number
30 GHz Verification Source	1043

Exposure Conditions

Phantom Section Position Te		Test Distance [mm]	Band	Frequency [MHz]
5G	FRONT	5.55	Validation band	30000 0

Hardware Setup

•			
Probe, Calibration Date	DAE, Calibration Date		
EUmmWV3 - SN9364, 06/24/2020	DAE4 SN1582, 04/15/2020		

Software Setup

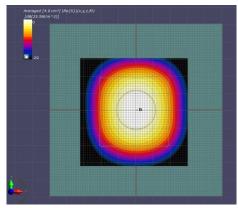
Software	Software Version		
cDASY6 Module mmWave	2.0.2.34		

Scans Setup

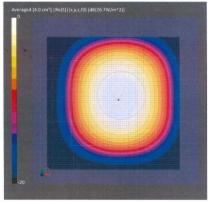
Scan Type	5G Scan
Grid Extents [mm]	60.0 × 60.0
Grid Steps [lambda]	0.25 x 0.25
Sensor Surface [mm]	5.55

Measurement Results

Scan Type	5G Scan
Avg. Area [cm²]	4.00
pS _{tot} avg [W/m ²]	25.5
pSn avg [W/m²]	25.2
E _{peak} [V/m]	115
Deviation (dB)	-0.20



30GHz System Verification



Calibration Certificate

APPENDIX B: SAR TISSUE SPECIFICATIONS

Measurement Procedure for Tissue verification:

- 1) The network analyzer and probe system was configured and calibrated.
- 2) The probe was immersed in the tissue. The tissue was placed in a nonmetallic container. Trapped air bubbles beneath the flange were minimized by placing the probe at a slight angle.
- 3) The complex admittance with respect to the probe aperture was measured
- 4) The complex relative permittivity ε can be calculated from the below equation (Pournaropoulos and Misra):

$$Y = \frac{j2\omega\varepsilon_{r}\varepsilon_{0}}{\left[\ln(b/a)\right]^{2}} \int_{a}^{b} \int_{0}^{a} \int_{0}^{\pi} \cos\phi' \frac{\exp\left[-j\omega r(\mu_{0}\varepsilon_{r}^{'}\varepsilon_{0})^{1/2}\right]}{r} d\phi' d\rho' d\rho$$

where Y is the admittance of the probe in contact with the sample, the primed and unprimed coordinates refer to

source and observation points, respectively, $r^2 = \rho^2 + {\rho'}^2 - 2\rho\rho'\cos\phi'$, ω is the angular frequency, and $j=\sqrt{-1}$.

3 Composition / Information on ingredients

CAS: 107-21-1	Ethanediol	>1.0-4.9%
EINECS: 203-473-3 Reg.nr.: 01-2119456816-28-0000	STOT RE 2, H373; Acute Tox, 4, H302	1 I I I I I I I I I I I I I I I I I I I
CAS: 68608-26-4 EINECS: 271-781-5 Reg.nr.: 01-2119527859-22-0000	Sodium petroleum sulfonate Eye Irrit. 2, H319	< 2.9%
CAS: 107-41-5 EINECS: 203-489-0 Reg.nr.: 01-2119539582-35-0000	Hexylene Glycol / 2-Methyl-pentane-2,4-diol Skin Irrit. 2, H315; Eye Irrit. 2, H319	< 2.9%
CAS: 68920-66-1 NLP: 500-236-9 Reg.nr.: 01-2119489407-26-0000	Alkoxylated alcohol, > C15 Aquatic Chronic 2, H411; Skin Irrit. 2, H315; Eye Irrit. 2, H319	< 2.0%

C

For the wording of the listed risk phrases refer to section 16. Not mentioned CAS-, EINECS- or registration numbers are to be regarded as Proprietary/Confidential. The specific chemical identity and/or exact percentage concentration of proprietary components is withheld as a trade secret.

Figure B -1

Note: Liquid recipes are proprietary SPEAG. Since the composition is approximate to the actual liquids utilized, the manufacturer tissue-equivalent liquid data sheets are provided below.

	FCC ID: A3LSMT978U		SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX B:
	07/21/2020 - 08/05/2020	Portable Tablet		Page 1 of 1
202	20 PCTEST			REV 1.0 04/06/2020

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Zeughausstrasse 43, 8004 Zurich, Switzerland Phone +41 44 245 9700, Fax +41 44 245 9779 info@speag.com, http://www.speag.com

Measurement Certificate / Material Test

Item Name	Body Tissue Simulating Liquid (MBBL600-6000V6)	
Product No.	SL AAM U16 BC (Batch: 181029-1)	
Manufacturer	SPEAG	

Measurement Method

TSL dielectric parameters measured using calibrated DAK probe.

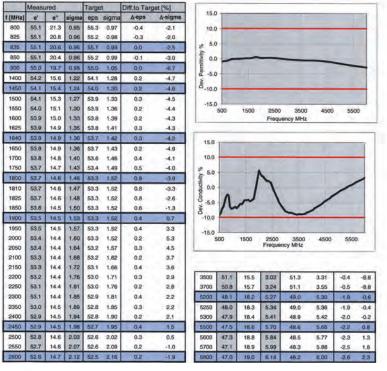
Target Parameters

Target parameters as defined in the KDB 865664 compliance standard.

Te

Test Condition	A second s	
Ambient Condition	22°C ; 30% humidity	
TSL Temperature	22°C	
Test Date	30-Oct-18	
Operator	CL	
Additional Inform	ation	
TSL Density		
TSL Heat-capacity		

Results



TSL Dielectric Parameters

Figure B-2 600 - 5800 MHz Body Tissue Equivalent Matter

	FCC ID: A3LSMT978U			Approved by: Quality Manager	
	Test Dates:	DUT Type:		APPENDIX B:	
	07/21/2020 - 08/05/2020	Portable Tablet		Page 2 of 2	
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APPENDIX C: SAR SYSTEM VALIDATION

Per FCC KDB Publication 865664 D02v01r02, SAR system validation status should be documented to confirm measurement accuracy. The SAR systems (including SAR probes, system components and software versions) used for this device were validated against its performance specifications prior to the SAR measurements. Reference dipoles were used with the required tissue- equivalent media for system validation, according to the procedures outlined in FCC KDB Publication 865664 D01v01r04 and IEEE 1528-2013. Since SAR probe calibrations are frequency dependent, each probe calibration point was validated at a frequency within the valid frequency range of the probe calibration point, using the system that normally operates with the probe for routine SAR measurements and according to the required tissue-equivalent media.

A tabulated summary of the system validation status including the validation date(s), measurement frequencies, SAR probes and tissue dielectric parameters has been included.

	System Validation												
SAR	Freq. (MHz)	Date	Probe				Perm.	CW	/ VALIDAT	ION	MOE). Validat	ION
System			SN	Probe Cal Point		Probe Cal Point	Cond. (σ)		SENSITIVITY	PROBE LINEARITY	PROBE ISOTROPY	MOD. TYPE	DUTY FACTOR
М	835	7/21/2020	7526	835	Body	0.989	54.877	PASS	PASS	PASS	GMSK	PASS	N/A
М	1750	5/19/2020	7526	1750	Body	1.507	51.979	PASS	PASS	PASS	N/A	N/A	N/A
М	1900	5/14/2020	7526	1900	Body	1.585	53.549	PASS	PASS	PASS	GMSK	PASS	N/A
М	2600	5/20/2020	7526	2600	Body	2.18	54.171	PASS	PASS	PASS	TDD	PASS	N/A

Table C-1 SAR System Validation Summary – 1g

NOTE: While the probes have been calibrated for both CW and modulated signals, all measurements were performed using communication systems calibrated for CW signals only. Modulations in the table above represent test configurations for which the measurement system has been validated per FCC KDB Publication 865664 D01v01r04 for scenarios when CW probe calibrations are used with other signal types. SAR systems were validated for modulated signals with a periodic duty cycle, such as GMSK, or with a high peak to average ratio (>5 dB), such as OFDM according to FCC KDB Publication 865664 D01v01r04.

FCC ID: A3LSMT978U	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Test Dates:	DUT Type:		APPENDIX C:
07/21/2020 - 08/05/2020	Portable Tablet		Page 1 of 1

APPENDIX E: TEST SEQUENCES

- 1. Test sequence is generated based on below parameters of the DUT:
 - a. Measured maximum power (Pmax)
 - b. Measured Tx_power_at_SAR_design_target (Plimit)
 - c. Reserve_power_margin (dB)
 - Preserve (dBm) = measured Plimit (dBm) Reserve_power_margin (dB)
 - d. SAR_time_window (100s for FCC)
- 2. Test Sequence 1 Waveform:

Based on the parameters above, the Test Sequence 1 is generated with one transition between high and low Tx powers. Here, high power = P_{max} ; low power = $P_{max}/2$, and the transition occurs after 80 seconds at high power P_{max} . As long as the power enforcement is taking into effective during one 100s/60s time window, the validation test with this defined test sequence 1 is valid, otherwise, select other radio configuration (band/DSI within the same technology group) having lower P_{limit} for this test. The Test sequence 1 waveform is shown below:

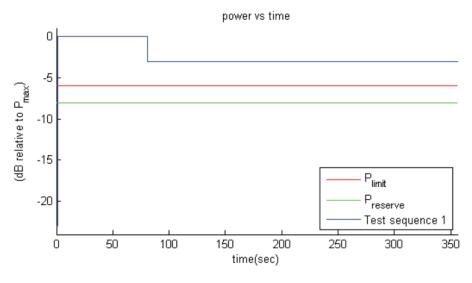


Figure E-1 Test sequence 1 waveform

	FCC ID: A3LSMT978U		SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Туре:		APPENDIX E:
	07/21/2020 - 08/05/2020	Portable Tablet		Page 1 of 3
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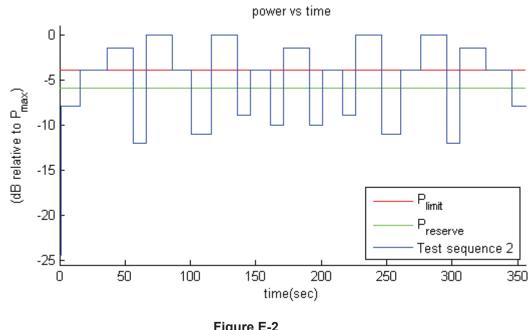
3. Test Sequence 2 Waveform:

Based on the parameters described above, the Test Sequence 2 is generated as described in Table 10-1, which contains two 170 second-long sequences (yellow and green highlighted rows) that are mirrored around the center row of 20s, resulting in a total duration of 360 seconds:

Time duration (seconds)	dB relative to <i>P_{limit}</i> or <i>P_{reserve}</i>	
<mark>15</mark>	P _{reserve} – 2	
20	P _{limit}	
20	(<i>P_{limit} + P_{max})</i> /2 averaged in mW and rounded to nearest 0.1 dB step	
<mark>10</mark>	P _{reserve} – 6	
20	P _{max}	
<mark>15</mark>	P _{limit}	
<mark>15</mark>	P _{reserve} – 5	
20	P _{max}	
<mark>10</mark>	P _{reserve} – 3	
<mark>15</mark>	P _{limit}	
<mark>10</mark>	P _{reserve} – 4	
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step	
10	P _{reserve} – 4	
15	P _{limit}	
10	P _{reserve} – 3	
20	P _{max}	
15	P _{reserve} – 5	
15	P _{limit}	
20	P _{max}	
10	P _{reserve} – 6	
20	(<i>P_{limit}</i> + <i>P_{max}</i>)/2 averaged in mW and rounded to nearest 0.1 dB step	
20	Plimit	
15	P _{reserve} – 2	

Table E-1 Test Sequence 2

	FCC ID: A3LSMT978U	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX E:
	07/21/2020 - 08/05/2020	Portable Tablet		Page 2 of 3
© 202	0 PCTEST			REV 1.0 04/06/2020



The Test Sequence 2 waveform is shown in Figure E-2.



	FCC ID: A3LSMT978U	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX E:
	07/21/2020 - 08/05/2020	Portable Tablet		Page 3 of 3
) 202	0 PCTEST			REV 1.0 04/06/2020

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APPENDIX F: TEST PROCEDURES FOR SUB6 NR + NR RADIO

Appendix F provides the test procedures for validating Qualcomm Smart Transmit feature for LTE + Sub6 NR non-standalone (NSA) mode transmission scenario, where sub-6GHz LTE link acts as an anchor.

F.1 Time-varying Tx power test for sub6 NR in NSA mode

Follows Section 4.2.1 to select test configurations for time-varying test. This test is performed with two pre-defined test sequences (described in Section 4.1) applied to Sub6 NR (with LTE on all-down bits or low power for the entire test after establishing the LTE+Sub6 NR call with the callbox). Follow the test procedures described in Section 4.3.1 to demonstrate the effectiveness of power limiting enforcement and that the time averaged Tx power of Sub6 NR when converted into 1gSAR values does not exceed the regulatory limit at all times (see Eq. (1a) and (1b)). Sub6 NR response to test sequence1 and test sequence2 will be similar to other technologies (say, LTE), and are shown in Sections 9.1.6 and 9.1.7.

F.2 Switch in SAR exposure between LTE vs. Sub6 NR during transmission

This test is to demonstrate that Smart Transmit feature accurately accounts for switching in exposures among SAR for LTE radio only, SAR from both LTE radio and sub6 NR, and SAR from sub6 NR only scenarios, and ensures total time-averaged RF exposure compliance with FCC limit.

Test procedure:

- 1. Measure conducted Tx power corresponding to P_{limit} for LTE and sub6 NR in selected band. Test condition to measure conducted P_{limit} is:
 - Establish device in call with the callbox for LTE in desired band. Measure conducted Tx power corresponding to LTE *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
 - Repeat above step to measure conducted Tx power corresponding to Sub6 NR <u>Plimit</u>. If testing LTE+Sub6 NR in non-standalone mode, then establish LTE+Sub6 NR call with callbox and request all down bits for radio1 LTE. In this scenario, with callbox requesting maximum power from Sub6 NR, measured conducted Tx power corresponds to radio2 <u>Plimit</u> (as radio1 LTE is at all-down bits)
- 2. Set Reserve_power_margin to actual (intended) value with EUT setup for LTE + Sub6 NR call. First, establish LTE connection in all-up bits with the callbox, and then Sub6 NR connection is added with callbox requesting UE to transmit at maximum power in Sub6 NR. As soon as the Sub6 NR connection is established, request all-down bits on LTE link (otherwise, Sub6 NR will not have sufficient RF exposure margin to sustain the call with LTE in all-up bits). Continue LTE (all-down bits)+Sub6 NR transmission for more than one time-window duration to test predominantly Sub6 NR SAR exposure scenario (as SAR exposure is negligible from all-down bits in LTE). After at least one time-window, request LTE to go all-up bits to test LTE SAR and Sub6 NR SAR exposure scenario. After at least one more time-window, drop (or request all-down bits) Sub6 NR transmission to test predominantly LTE SAR exposure scenario. Continue the test for at least one more time-window. Record the conducted Tx powers for both LTE and Sub6 NR for the entire duration of this test.

- 3. Once the measurement is done, extract instantaneous Tx power versus time for both LTE and Sub6 NR links. Similar to technology/band switch test in Section 4.3.3, convert the conducted Tx power for both these radios into 1gSAR value (see Eq. (6a) and (6b)) using corresponding technology/band *P*_{limit} measured in Step 1, and then perform 100s running average to determine time-averaged 1gSAR versus time as illustrated in Figure 4-1. Note that here it is assumed both radios have Tx frequencies < 3GHz, otherwise, 60s running average should be performed for radios having Tx frequency between 3GHz and 6GHz.</p>
- 4. Make one plot containing: (a) instantaneous Tx power versus time measured in Step 2.
- Make another plot containing: (a) instantaneous 1gSAR versus time determined in Step 3, (b) computed time-averaged 1gSAR versus time determined in Step 3, and (c) corresponding regulatory 1gSAR_{limit} of 1.6W/kg.

The validation criteria is, at all times, the time-averaged 1gSAR versus time shall not exceed the regulatory *1gSAR*_{*limit*} of 1.6W/kg.